- **Highest Performance Floating-Point Digital** Signal Processor (DSP) SMJ320C6701
 - 7-, 6-ns Instruction Cycle Time
 - 140-, 167-MHz Clock Rate
 - Eight 32-Bit Instructions/Cycle
 - Up to 1 GFLOPS Performance
 - Pin-Compatible With 'C6201 Fixed-Point
- SMJ: QML Processing to MIL-PRF-38535
- SM: Standard Processing
- **Operating Temperature Ranges**
 - Extended (W) –55°C to 115°C
 - Extended (S) –40°C to 90°C
- VelociTI™ Advanced Very Long Instruction Word (VLIW) 'C67x CPU Core
 - Eight Highly Independent Functional Units:
 - Four ALUs (Floating- and Fixed-Point)
 - Two ALUs (Fixed-Point)
 - Two Multipliers (Floating- and Fixed-Point)
 - Load-Store Architecture With 32 32-Bit **General-Purpose Registers**
 - Instruction Packing Reduces Code Size
 - All Instructions Conditional
- **Instruction Set Features**
 - Hardware Support for IEEE **Single-Precision Instructions**
 - Hardware Support for IEEE **Double-Precision Instructions**
 - Byte-Addressable (8-, 16-, 32-Bit Data)
 - 32-Bit Address Range
 - 8-Bit Overflow Protection
 - Saturation
 - Bit-Field Extract, Set, Clear
 - Bit-Counting
 - Normalization

- 1M-Bit On-Chip SRAM
 - 512K-Bit Internal Program/Cache (16K 32-Bit Instructions)
 - 512K-Bit Dual-Access Internal Data (64K Bytes)
- 32-Bit External Memory Interface (EMIF)
 - Glueless Interface to Synchronous Memories: SDRAM and SBSRAM
 - **Glueless Interface to Asynchronous Memories: SRAM and EPROM**
- **Four-Channel Bootloading** Direct-Memory-Access (DMA) Controller With an Auxiliary Channel
- 16-Bit Host-Port Interface (HPI)
 - Access to Entire Memory Map
- Two Multichannel Buffered Serial Ports (McBSPs)
 - Direct Interface to T1/E1, MVIP, SCSA Framers
 - ST-Bus-Switching Compatible
 - Up to 256 Channels Each
 - AC97-Compatible
 - Serial-Peripheral-Interface (SPI) Compatible (Motorola™)
- Two 32-Bit General-Purpose Timers
- Flexible Phase-Locked-Loop (PLL) Clock Generator
- IEEE-1149.1 (JTAG[†]) **Boundary-Scan-Compatible**
- 429-Pin Ceramic Ball Grid Array (CBGA) Package (GLP Suffix)
- 0.18-μm/5-Level Metal Process
 - CMOS Technology
- 3.3-V I/Os, 1.9-V Internal



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

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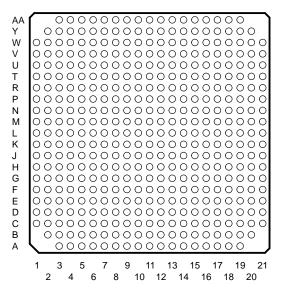
Motorola is a trademark of Motorola, Inc.

TIFEE Standard 1149.1-1990 Standard-Test-Access Port and Boundary Scan Architecture.



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description

The SMJ320C67x DSPs are the floating-point DSP family in the SMJ320C6000 platform. The SMJ320C6701 ('C6701) device is based on the high-performance, advanced VelociTI very-long-instruction-word (VLIW) architecture developed by Texas Instruments (TI™), making this DSP an excellent choice for multichannel and multifunction applications. With performance of up to 1 giga floating-point operations per second (GFLOPS) at a clock rate of 167 MHz, the 'C6701 offers cost-effective solutions to high-performance DSP programming challenges. The 'C6701 DSP possesses the operational flexibility of high-speed controllers and the numerical capability of array processors. This processor has 32 general-purpose registers of 32-bit word length and eight highly independent functional units. The eight functional units provide four floating-/fixed-point ALUs, two fixed-point ALUs, and two floating-/fixed-point multipliers. The 'C6701 can produce two multiply-accumulates (MACs) per cycle for a total of 334 million MACs per second (MMACS). The 'C6701 DSP also has application-specific hardware logic, on-chip memory, and additional on-chip peripherals.

The 'C6701 includes a large bank of on-chip memory and has a powerful and diverse set of peripherals. Program memory consists of a 64K-byte block that is user-configurable as cache or memory-mapped program space. Data memory consists of two 32K-byte blocks of RAM. The peripheral set includes two multichannel buffered serial ports (McBSPs), two general-purpose timers, a host-port interface (HPI), and a glueless external memory interface (EMIF) capable of interfacing to SDRAM or SBSRAM and asynchronous peripherals.

The 'C6701 has a complete set of development tools which includes: a new C compiler, an assembly optimizer to simplify programming and scheduling, and a Windows™ debugger interface for visibility into source code execution.



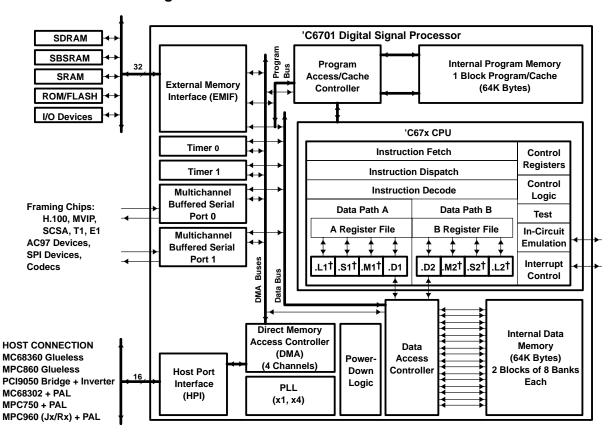
device characteristics

Table 1 provides an overview of the 'C6701 DSP. The table shows significant features of each device, including the capacity of on-chip RAM, the peripherals, the execution time, and the package type with pin count.

Table 1. Characteristics of the 'C6701 Processors

CHARACTERISTICS	DESCRIPTION
Device Number	SMJ320C6701
On-Chip Memory	512-Kbit Program Memory 512-Kbit Data Memory (organized as 2 blocks)
Peripherals	2 Mutichannel Buffered Serial Ports (McBSP) 2 General-Purpose Timers Host-Port Interface (HPI) External Memory Interface (EMIF)
Cycle Time	7 ns at 140 MHz, and 6 ns at 167 MHz
Package Type	27 mm × 27 mm, 429-Pin BGA (GLP)
Nominal Voltage	1.9 V Core 3.3 V I/O

functional and CPU block diagram



[†] These functional units execute floating-point instructions.



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CPU description

The CPU fetches VelociTI advanced very-long instruction words (VLIW) (256 bits wide) to supply up to eight 32-bit instructions to the eight functional units during every clock cycle. The VelociTI VLIW architecture features controls by which all eight units do not have to be supplied with instructions if they are not ready to execute. The first bit of every 32-bit instruction determines if the next instruction belongs to the same execute packet as the previous instruction, or whether it should be executed in the following clock as a part of the next execute packet. Fetch packets are always 256 bits wide; however, the execute packets can vary in size. The variable-length execute packets are a key memory-saving feature, distinguishing the 'C67x CPU from other VLIW architectures.

The CPU features two sets of functional units. Each set contains four units and a register file. One set contains functional units .L1, .S1, .M1, and .D1; the other set contains units .D2, .M2, .S2, and .L2. The two register files contain 16 32-bit registers each for the total of 32 general-purpose registers. The two sets of functional units, along with two register files, compose sides A and B of the CPU (see the functional and CPU block diagram and Figure 1). The four functional units on each side of the CPU can freely share the 16 registers belonging to that side. Additionally, each side features a single data bus connected to all registers on the other side, by which the two sets of functional units can access data from the register files on opposite sides. While register access by functional units on the same side of the CPU as the register file can service all the units in a single clock cycle, register access using the register file across the CPU supports one read and one write per cycle.

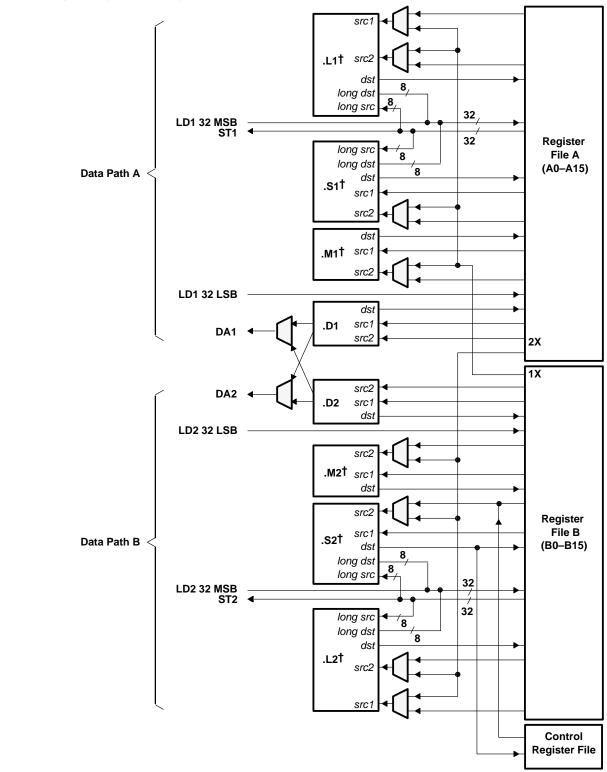
The 'C67x CPU executes all 'C62x instructions. In addition to 'C62x fixed-point instructions, the six out of eight functional units (.L1, .M1, .D1, .D2, .M2, and .L2) also execute floating-point instructions. The remaining two functional units (.S1 and .S2) also execute the new LDDW instruction which loads 64 bits per CPU side for a total of 128 bits per cycle.

Another key feature of the 'C67x CPU is the load/store architecture, where all instructions operate on registers (as opposed to data in memory). Two sets of data-addressing units (.D1 and .D2) are responsible for all data transfers between the register files and the memory. The data address driven by the .D units allows data addresses generated from one register file to be used to load or store data to or from the other register file. The 'C67x CPU supports a variety of indirect-addressing modes using either linear- or circular-addressing modes with 5- or 15-bit offsets. All instructions are conditional, and most can access any one of the 32 registers. Some registers, however, are singled out to support specific addressing or to hold the condition for conditional instructions (if the condition is not automatically "true"). The two .M functional units are dedicated for multiplies. The two .S and .L functional units perform a general set of arithmetic, logical, and branch functions with results available every clock cycle.

The processing flow begins when a 256-bit-wide instruction fetch packet is fetched from a program memory. The 32-bit instructions destined for the individual functional units are "linked" together by "1" bits in the least significant bit (LSB) position of the instructions. The instructions that are "chained" together for simultaneous execution (up to eight in total) compose an execute packet. A "0" in the LSB of an instruction breaks the chain, effectively placing the instructions that follow it in the next execute packet. If an execute packet crosses the fetch-packet boundary (256 bits wide), the assembler places it in the next fetch packet, while the remainder of the current fetch packet is padded with NOP instructions. The number of execute packets within a fetch packet can vary from one to eight. Execute packets are dispatched to their respective functional units at the rate of one per clock cycle and the next 256-bit fetch packet is not fetched until all the execute packets from the current fetch packet have been dispatched. After decoding, the instructions simultaneously drive all active functional units for a maximum execution rate of eight instructions every clock cycle. While most results are stored in 32-bit registers, they can be subsequently moved to memory as bytes or half-words as well. All load and store instructions are byte-, half-word, or word-addressable.



CPU description (continued)



[†] These functional units execute floating-point instructions.

Figure 1. SMJ320C67x CPU Data Paths



signal groups description

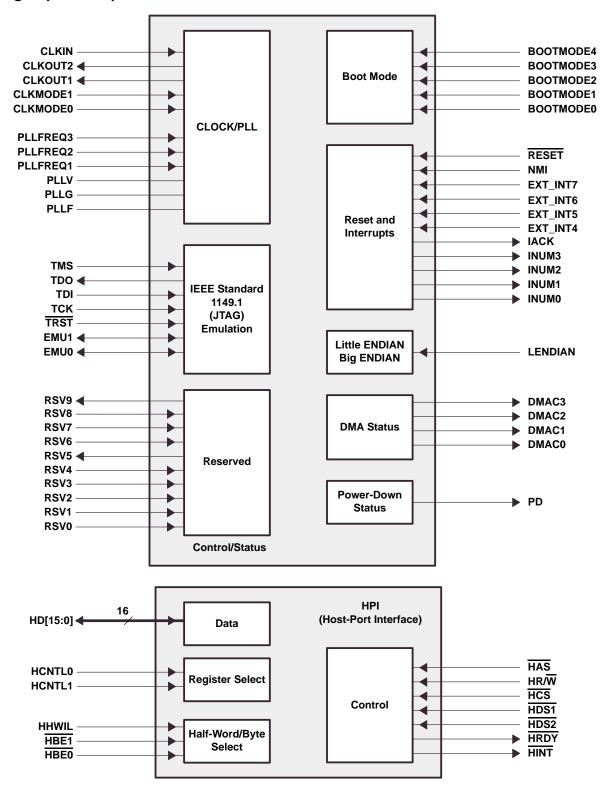


Figure 2. CPU and Peripheral Signals



signal groups description (continued)

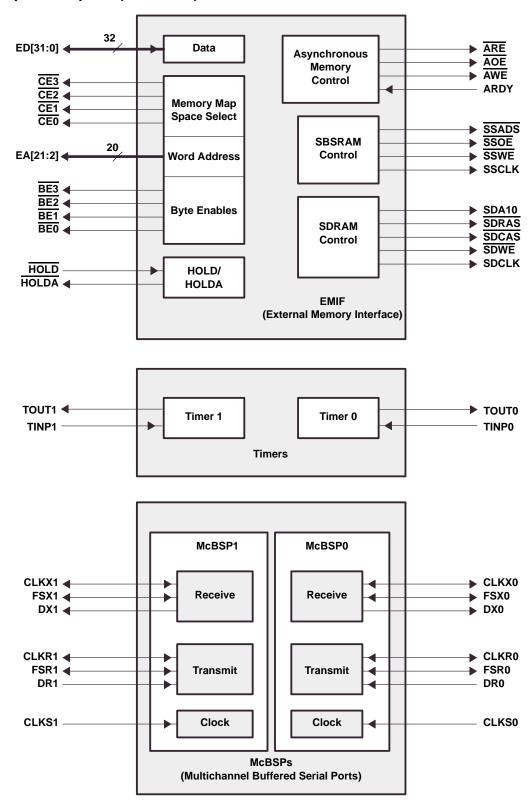


Figure 3. Peripheral Signals

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Signal Descriptions

SIGNAL .						
NAME	NO.	TYPET	DESCRIPTION			
	CLOCK/PLL					
CLKIN	A14	ı	Clock Input			
CLKOUT1	Y6	0	Clock output at full device speed			
CLKOUT2	V9	0	Clock output at half of device speed			
CLKMODE1	B17		Clock mode select			
CLKMODE0	C17		Selects whether the output clock frequency = input clock freq x4 or x1			
PLLFREQ3	C13		PLL frequency range (3, 2, and 1)			
PLLFREQ2	G11	l ı	The target range for CLKOUT1 frequency is determined by the 3-bit value of the PLLFREQ pins.			
PLLFREQ1	F11					
PLLV [‡]	D12	Α§	PLL analog V _{CC} connection for the low-pass filter			
PLLG [‡]	G10	Α§	PLL analog GND connection for the low-pass filter			
PLLF	C12	Α§	PLL low-pass filter connection to external components and a bypass capacitor			
		•	JTAG EMULATION			
TMS	K19	I	JTAG test port mode select (features an internal pull-up)			
TDO	R12	O/Z	JTAG test port data out			
TDI	R13	ı	JTAG test port data in (features an internal pull-up)			
TCK	M20	ı	JTAG test port clock			
TRST	N18	ı	JTAG test port reset (features an internal pull-down)			
EMU1	R20	I/O/Z	Emulation pin 1, pull-up with a dedicated 20-kΩ resistor¶			
EMU0	T18	I/O/Z	Emulation pin 0, pull-up with a dedicated 20-kΩ resistor¶			
			RESET AND INTERRUPTS			
RESET	J20	ı	Device reset			
NMI	K21	1	Nonmaskable interrupt • Edge-driven (rising edge)			
EXT_INT7	R16					
EXT_INT6	P20] .	External interrupts			
EXT_INT5	R15] I	Edge-driven (rising edge)			
EXT_INT4	R18					
IACK	R11	0	Interrupt acknowledge for all active interrupts serviced by the CPU			
INUM3	T19					
INUM2	T20		Active interrupt identification number • Valid during IACK for all active interrupts (not just external)			
INUM1	T14	0	Valid during IACK for all active interrupts (not just external) Encoding order follows the interrupt service fetch packet ordering			
INUM0	T16		·			
	LITTLE ENDIAN/BIG ENDIAN					
LENDIAN	G20	I	If high, selects little-endian byte/half-word addressing order within a word If low, selects big-endian addressing			
			POWER DOWN STATUS			
PD	D19	0	Power-down mode 2 or 3 (active if high)			

[¶] For emulation and normal operation, pull up EMU1 and EMU0 with a dedicated 20-kΩ resistor. For boundary scan, pull down EMU1 and EMU0 with a dedicated 20-k Ω resistor.



[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground ‡ PLLV and PLLG signals are not part of external voltage supply or ground. See the CLOCK/PLL documentation for information on how to connect those pins.

[§] A = Analog Signal (PLL Filter)

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SIGNAL	_	_	Cigital Descriptions (Continued)			
NAME	NO.	TYPET	DESCRIPTION			
	HOST PORT INTERFACE (HPI)					
HINT	H2	O/Z	Host interrupt (from DSP to host)			
HCNTL1	J6	I	Host control – selects between control, address or data registers			
HCNTL0	H6	ı	Host control – selects between control, address or data registers			
HHWIL	E4	I	Host halfword select – first or second halfword (not necessarily high or low order)			
HBE1	G6	I	Host byte select within word or half-word			
HBE0	F6	I	Host byte select within word or half-word			
HR/W	D4	I	Host read or write select			
HD15	D11					
HD14	B11	1				
HD13	A11					
HD12	G9	1				
HD11	D10	1				
HD10	A10	1				
HD9	C10	1				
HD8	B9		Host port data (used for transfer of data, address and control)			
HD7	F9	I/O/Z				
HD6	C9	1				
HD5	A9	1				
HD4	B8	1				
HD3	D9					
HD2	D8					
HD1	B7	1				
HD0	C7					
HAS	L6	I	Host address strobe			
HCS	C5	I	Host chip select			
HDS1	C4	I	Host data strobe 1			
HDS2	K6	I	Host data strobe 2			
HRDY	НЗ	0	Host ready (from DSP to host)			
			BOOT MODE			
BOOTMODE4	B16					
BOOTMODE3	G14					
BOOTMODE2	F15	I	Boot mode			
BOOTMODE1	C18					
BOOTMODE0	D17					



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SIGNA	L	_				
NAME	NO.	TYPET	DESCRIPTION			
	EMIF - CONTROL SIGNALS COMMON TO ALL TYPES OF MEMORY					
CE3	Y5	O/Z				
CE2	V3	O/Z	Memory space enables			
CE1	T6	O/Z	Enabled by bits 24 and 25 of the word address			
CE0	U2	O/Z	Only one asserted during any external data access			
BE3	R8	O/Z	Byte enable control			
BE2	Т3	O/Z	Decoded from the two lowest bits of the internal address			
BE1	T2	O/Z	Byte write enables for most types of memory			
BE0	R2	O/Z	Can be directly connected to SDRAM read and write mask signal (SDQM)			
			EMIF – ADDRESS			
EA21	L4					
EA20	L3					
EA19	J2					
EA18	J1					
EA17	K1					
EA16	K2					
EA15	L2					
EA14	L1					
EA13	M1					
EA12	M2	0/7	Estample address (ward address)			
EA11	M6	O/Z	External address (word address)			
EA10	N4					
EA9	N1					
EA8	N2					
EA7	N6					
EA6	P4					
EA5	P3					
EA4	P2					
EA3	P1					
EA2	P6					

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SIGNA	L					
NAME	NO.	TYPET	DESCRIPTION			
	EMIF – DATA					
ED31	U18					
ED30	U20					
ED29	T15					
ED28	V18					
ED27	V17					
ED26	V16					
ED25	T12					
ED24	W17					
ED23	T13					
ED22	Y17					
ED21	T11					
ED20	Y16					
ED19	W15					
ED18	V14					
ED17	Y15					
ED16	R9	1/0/7	Estamal data			
ED15	Y14	I/O/Z	External data			
ED14	V13					
ED13	AA13					
ED12	T10					
ED11	Y13					
ED10	W12					
ED9	Y12					
ED8	Y11					
ED7	V10					
ED6	AA10					
ED5	Y10					
ED4	W10					
ED3	Y9					
ED2	AA9					
ED1	Y8					
ED0	W9					
			EMIF – ASYNCHRONOUS MEMORY CONTROL			
ARE	R7	O/Z	Asynchronous memory read enable			
AOE	T7	O/Z	Asynchronous memory output enable			
AWE	V5	O/Z	Asynchronous memory write enable			
ARDY	R4	I	Asynchronous memory ready input			

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SIGNAL .						
NAME	NO.	TYPET	DESCRIPTION			
	EMIF – SYNCHRONOUS BURST SRAM CONTROL					
SSADS	V8	O/Z	SBSRAM address strobe			
SSOE	W7	O/Z	SBSRAM output enable			
SSWE	Y7	O/Z	SBSRAM write enable			
SSCLK	AA8	O/Z	SBSRAM clock			
			EMIF – SYNCHRONOUS DRAM CONTROL			
SDA10	V7	O/Z	SDRAM address 10 (separate for deactivate command)			
SDRAS	V6	O/Z	SDRAM row address strobe			
SDCAS	W5	O/Z	SDRAM column address strobe			
SDWE	T8	O/Z	SDRAM write enable			
SDCLK	Т9	O/Z	SDRAM clock			
			EMIF – BUS ARBITRATION			
HOLD	R6	I	Hold request from the host			
HOLDA	B15	0	Hold request acknowledge to the host			
		_	TIMERS			
TOUT1	G2	O/Z	Timer 1 or general-purpose output			
TINP1	K3	I	Timer 1 or general-purpose input			
TOUT0	M18	O/Z	Timer 0 or general-purpose output			
TINP0	J18	I	Timer 0 or general-purpose input			
			DMA ACTION COMPLETE			
DMAC3	E18					
DMAC2	F19	0	DMA pation complete			
DMAC1	E20		DMA action complete			
DMAC0	G16					
			MULTICHANNEL BUFFERED SERIAL PORT 1 (McBSP1)			
CLKS1	F4	- 1	External clock source (as opposed to internal)			
CLKR1	H4	I/O/Z	Receive clock			
CLKX1	J4	I/O/Z	Transmit clock			
DR1	E2	- 1	Receive data			
DX1	G4	O/Z	Transmit data			
FSR1	F3	I/O/Z	Receive frame sync			
FSX1	F2	I/O/Z	Transmit frame sync			

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SIGNA	SIGNAL SIGNAL			
NAME	NO.	TYPET	DESCRIPTION	
		1	MULTICHANNEL BUFFERED SERIAL PORT 0 (McBSP0)	
CLKS0	K18	ı	External clock source (as opposed to internal)	
CLKR0	L21	I/O/Z	Receive clock	
CLKX0	K20	I/O/Z	Transmit clock	
DR0	J21	ı	Receive data	
DX0	M21	O/Z	Transmit data	
FSR0	P16	I/O/Z	Receive frame sync	
FSX0	N16	I/O/Z	Transmit frame sync	
			RESERVED FOR TEST	
RSV0	N21	I	Reserved for testing, pull-up with a dedicated 20-kΩ resistor	
RSV1	K16	I	Reserved for testing, pull-up with a dedicated 20-kΩ resistor	
RSV2	B13	I	Reserved for testing, pull-up with a dedicated 20-kΩ resistor	
RSV3	B14	I	Reserved for testing, pull-up with a dedicated 20-kΩ resistor	
RSV4	F13	I	Reserved for testing, <i>pull-down</i> with a dedicated 20-k Ω resistor	
RSV5	C15	0	Reserved (leave unconnected, do not connect to power or ground)	
RSV6	F7	I	Reserved for testing, pull-up with a dedicated 20-kΩ resistor	
RSV7	D7	I	Reserved for testing, pull-up with a dedicated 20-kΩ resistor	
RSV8	B5	I	Reserved for testing, pull-up with a dedicated 20-kΩ resistor	
RSV9	F16	0	Reserved (leave unconnected, do not connect to power or ground)	
			SUPPLY VOLTAGE PINS	
	C14]		
	C8]		
	E19			
	E3]		
	H11]		
	H13			
	H9			
	J10			
	J12	1		
	J14			
DV_{DD}	J19	s	3.3-V supply voltage	
	J3]		
	J8	1		
	K11	1		
	K13	1		
	K15	1		
	K7	1		
	K9	1		
	L10	1		
	L12	1		
	L14	1		

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SIGNAL	Signal Descriptions (Continued)					
NAME	NO.	TYPET	DESCRIPTION			
	SUPPLY VOLTAGE PINS (CONTINUED)					
	L8					
	M11					
	M13					
	M15					
	M7					
	M9	1				
	N10					
	N12					
	N14					
DV_{DD}	N19	S	3.3-V supply voltage			
	N3]				
	N8					
	P11					
	P13					
	P9					
	U19					
	U3					
	W14					
	W8	ļ				
	A12					
	A13					
	B10 B12					
	B6	1				
	D15					
	D16					
	F10	1				
	F14					
	F8	1				
CV _{DD}	G13	S	1.9-V supply voltage			
	G7	1				
	G8	1				
	K4	1				
	М3	1				
	M4					
	А3					
	A5					
	A7					
	A16					

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SIGNAL			Cigital Descriptions (Continued)
NAME	NO.	TYPET	DESCRIPTION
			SUPPLY VOLTAGE PINS (CONTINUED)
	A18		
	AA4	_	
	AA6		
	AA15		
	AA17		
	AA19		
	B2		
	B4		
	B19	ļ	
	C1		
	C3	-	
	C20 D2	ł	
	D21		
	E1	-	
	E6		
	E8		
CV _{DD}	E10	S	1.9-V supply voltage
	E12		
	E14		
	E16	1	
	F5	1	
	F17		
	F21		
	G1		
	H5		
	H17		
	K5		
	K17		
	M5		
	M17		
	P5		
	P17 R21	-	

R21 | The Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

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SIGNAL			Oignal Descriptions (Continued)
NAME	NO.	TYPET	DESCRIPTION
			SUPPLY VOLTAGE PINS (CONTINUED)
	T1		
	T5	1	
	T17		
	U6		
	U8		
	U10		
	U12		
	U14		
	U16		
	U21		
	V1		
	V20		
	W2		
	W19		
	W21	S	
	Y3		
	Y18		
	Y20		
CVDD	AA11		1.9-V supply voltage
	AA12		
	F20	- - -	
	G18		
	H16 H18		
	L18		
	L19	1	
	L20	1	
	N20	1	
	P18	1	
	P19	1	
	R10	1	
	R14	1	
	U4	1	
	V11	-	
	V12		
	V15		
	W13	1	

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SIGNAL			Signal Descriptions (Continued)					
NAME	NO.	TYPET	DESCRIPTION					
	GROUND PINS							
	C11							
	C16							
	C6							
	D5							
	G3							
	H10							
	H12							
	H14							
	H7							
	H8							
	J11							
	J13							
	J7							
	J9]						
	K8							
	L7							
	L9							
	M8							
	N7							
VSS	R3	GND	Ground pins					
	A4							
	A6							
	A8							
	A15							
	A17							
	A19							
	AA3							
	AA5							
	AA7							
	AA14							
	AA16 AA18							
	B3							
	B18							
	B20							
	C2	1						
	C19							
	C21							
	D1							

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SIGNAL		TYPET	DESCRIPTION
NAME	NO.	ITPEI	DESCRIPTION
			GROUND PINS (CONTINUED)
	D20		
	E5		
	E7		
	E9		
	E11		
	E13		
	E15		
	E17		
	E21		
	F1		
	G5 G17		
	G21		
	H1		
	J5	GND	
	J17		
	L5		
V _{SS}	L17		Ground pins
.33	N5		Siound Pillo
	N17		
	P21		
	R1		
	R5		
	R17		
	T21		
	U1		
	U5		
	U7		
	U9		
	U11		
	U13		
	U15		
	U17		
	V2		
	V21		

[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



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SIGNA	L		Olgital Descriptions (Gentinaea)	
NAME	NO.	TYPET	DESCRIPTION	
			GROUND PINS (CONTINUED)	
	W1 W3			
	W20			
	Y2			
	Y4			
	Y19			
	F18			
	G19			
	H15			
	J15			
	J16			
	K10			
	K12			
	K14			
	L11]		
	L13			
	L15			
VSS	M10	GND	Ground pins	
	M12			
	M14			
	N11			
	N13			
	N15			
	N9			
	P10			
	P12			
	P14			
	P15			
	P7 P8			
	R19			
	T4			
	W11			
	W16			
	W6			

[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground



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SIGNA	L		D=00010=1011						
NAME	NO.	TYPET	DESCRIPTION						
	REMAINING UNCONNECTED PINS								
	D13								
	D14								
	D18								
	D3								
	D6								
	F12								
	G12								
	G15								
NC	H19		Unconnected pins						
140	H20		oneometica pins						
	H21								
	L16								
	M16								
	M19								
	V19								
	V4								
	W18								
	W4								

[†] I = Input, O = Output, Z = High Impedance, S = Supply Voltage, GND = Ground

development support

Texas Instruments (TI) offers an extensive line of development tools for the 'C6x generation of DSPs, including tools to evaluate the performance of the processors, generate code, develop algorithm implementations, and fully integrate and debug software and hardware modules.

The following products support development of 'C6x-based applications:

Software-Development Tools:

Assembly optimizer
Assembler/Linker
Simulator
Optimizing ANSI C compiler
Application algorithms
C/Assembly debugger and code profiler

Hardware-Development Tools:

Extended development system (XDS™) emulator (supports 'C6x multiprocessor system debug) EVM (Evaluation Module)

The *TMS320 DSP Development Support Reference Guide* (SPRU011) contains information about development-support products for all TMS320 family member devices, including documentation. See this document for further information on TMS320 documentation or any TMS320 support products from Texas Instruments. An additional document, the *TMS320 Third-Party Support Reference Guide* (SPRU052), contains information about TMS320-related products from other companies in the industry. To receive TMS320 literature, contact the Literature Response Center at 800/477-8924.

See Table 2 for a complete listing of development-support tools for the 'C6x. For information on pricing and availability, contact the nearest TI field sales office or authorized distributor.

Table 2. SMJ320C6x Development-Support Tools

DEVELOPMENT TOOL	PLATFORM	PART NUMBER
	Software	
Ada 95 Compiler [†]	Sun Solaris 2.3™‡	AD0345AS8500RF - Single User AD0345BS8500RF - Multi-user
C Compiler/Assembler/Linker/Assembly Optimizer	Win32™	TMDX3246855-07
C Compiler/Assembler/Linker/Assembly Optimizer	SPARC™ Solaris™	TMDX3246555-07
Simulator	Win32	TMDS3246851-07
Simulator	SPARC Solaris	TMDS3246551-07
XDS510™ Debugger/Emulation Software	Win32, Windows NT™	TMDX324016X-07
	Hardware	
XDS510 Emulator§	PC	TMDS00510
XDS510WS™ Emulator¶	SCSI	TMDS00510WS
	Software/Hardware	
EVM Evaluation Kit	PC/Win95/Windows NT	TMDX3260A6201
EVM Evaluation Kit (including TMDX3246855–07)	PC/Win95/Windows NT	TMDX326006201

[†] Contact IRVINE Compiler Corporation (949) 250-1366 to order.

Solaris is a trademark of Sun Microsystems, Inc.



[‡]NT support estimated availability 1Q00.

[§] Includes XDS510 board and JTAG emulation cable. TMDX324016X-07 C-source Debugger/Emulation software is not included.

 $[\]P$ Includes XDS510WS box, SCSI cable, power supply, and JTAG emulation cable.

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device and development-support tool nomenclature

To designate the stages in the product-development cycle, TI assigns prefixes to the part numbers of all SMJ320 devices and support tools. Each SMJ320 member has one of three prefixes: SMX, SM, or SMJ. Texas Instruments recommends two of three possible prefix designators for support tools: TMDX and TMDS. These prefixes represent evolutionary stages of product development from engineering prototypes (SMX/TMDX) through fully qualified production devices/tools (SMJ/TMDS).

Device development evolutionary flow:

SMX Experimental device that is not necessarily representative of the final device's electrical

specifications

SM Final silicon die that conforms to the device's electrical specifications but has not completed

quality and reliability verification

SMJ Fully qualified production device processed to MIL-PRF-38535

Support tool development evolutionary flow:

TMDX Development-support product that has not yet completed Texas Instruments internal qualification

testing.

TMDS Fully qualified development-support product

SMX devices and TMDX development-support tools are shipped against the following disclaimer:

"Developmental product is intended for internal evaluation purposes."

SMJ devices and TMDS development-support tools have been characterized fully, and the quality and reliability of the device have been demonstrated fully. TI's standard warranty applies.

Predictions show that prototype devices (SMX or SM) have a greater failure rate than the standard production devices. Texas Instruments recommends that these devices not be used in any production system because their expected end-use failure rate still is undefined. Only qualified production devices are to be used.

TI device nomenclature also includes a suffix with the device family name. This suffix indicates the package type (for example, GLP), the temperature range, and the device speed range in megahertz (for example, 16 is 167 MHz). Figure 4 provides a legend for reading the complete device name for any SMJ320 family member.



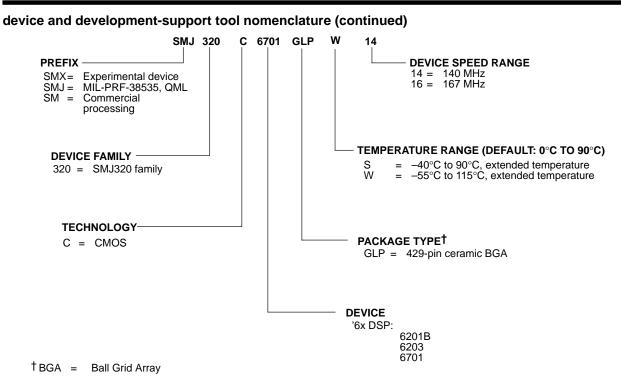


Figure 4. SMJ320 Device Nomenclature (Including SMJ320C6701)

documentation support

Extensive documentation supports all SMJ320 family generations of devices from product announcement through applications development. The types of documentation available include: data sheets, such as this document, with design specifications; complete user's reference guides for all devices; technical briefs; development-support tools; and hardware and software applications. The following is a brief, descriptive list of support documentation specific to the 'C6x devices:

The *TMS320C6000 CPU and Instruction Set Reference Guide* (literature number SPRU189) describes the 'C6000 CPU architecture, instruction set, pipeline, and associated interrupts.

The *TMS320C6000 Peripherals Reference Guide* (literature number SPRU190) describes the functionality of the peripherals available on 'C6x devices, such as the external memory interface (EMIF), host-port interface (HPI), multichannel buffered serial ports (McBSPs), direct-memory-access (DMA), enhanced direct-memory-access (EDMA) controller, expansion bus (XB), clocking and phase-locked loop (PLL); and power-down modes. This guide also includes information on internal data and program memories.

The *TMS320C6000 Programmer's Guide* (literature number SPRU198) describes ways to optimize C and assembly code for 'C6x devices and includes application program examples.

The *TMS320C6x C Source Debugger User's Guide* (literature number SPRU188) describes how to invoke the 'C6x simulator and emulator versions of the C source debugger interface and discusses various aspects of the debugger, including: command entry, code execution, data management, breakpoints, profiling, and analysis.

The TMS320C6x Peripheral Support Library Programmer's Reference (literature number SPRU273) describes the contents of the 'C6x peripheral support library of functions and macros. It lists functions and macros both by header file and alphabetically, provides a complete description of each, and gives code examples to show how they are used.



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documentation support (continued)

TMS320C6000 Assembly Language Tools User's Guide (literature number SPRU186) describes the assembly language tools (assembler, linker, and other tools used to develop assembly language code), assembler directives, macros, common object file format, and symbolic debugging directives for the 'C6000 generation of devices.

The *TMS320C6x Evaluation Module Reference Guide* (literature number SPRU269) provides instructions for installing and operating the 'C6x evaluation module. It also includes support software documentation, application programming interfaces, and technical reference material.

TMS320C6000 DSP/BIOS User's Guide (literature number SPRU303) describes how to use DSP/BIOS tools and APIs to analyze embedded real-time DSP applications.

Code Composer User's Guide (literature number SPRU296) explains how to use the Code Composer development environment to build and debug embedded real-time DSP applications.

Code Composer Studio Tutorial (literature number SPRU301) introduces the Code Composer Studio integrated development environment and software tools.

The *TMS320C6000 Technical Brief* (literature number SPRU197) gives an introduction to the 'C62x/C67x devices, associated development tools, and third-party support.

A series of DSP textbooks is published by Prentice-Hall and John Wiley & Sons to support DSP research and education. The TMS320 newsletter, *Details on Signal Processing*, is published quarterly and distributed to update SMJ320 customers on product information. The TMS320 DSP bulletin board service (BBS) provides access to information pertaining to the SMJ320 family, including documentation, source code, and object code for many DSP algorithms and utilities. The BBS can be reached at 281/274-2323.

Information regarding TI DSP products is also available on the Worldwide Web at http://www.ti.com uniform resource locator (URL).

clock PLL

All of the internal 'C67x clocks are generated from a single source through the CLKIN pin. This source clock either drives the PLL, which multiplies the source clock in frequency to generate the internal CPU clock, or bypasses the PLL to become the internal CPU clock.

To use the PLL to generate the CPU clock, the external PLL filter circuit must be properly designed. Table 3, Table 4, and Figure 5 show the external PLL circuitry for either x1 (PLL bypass) or x4 PLL multiply modes. Table 3 and Figure 6 show the external PLL circuitry for a system with ONLY x1 (PLL bypass) mode.

To minimize the clock jitter, a single clean power supply should power both the 'C67x device and the external clock oscillator circuit. Noise coupling into PLLF will directly impact PLL clock jitter. The minimum CLKIN rise and fall times should also be observed. For the input clock timing requirements, see the *input and output clocks* electricals section. Guidelines for EMI filter selection are as follows: maximum attenuation frequency = 20-30 MHz, maximum dB attenuation = 45-50 dB, and minimum dB attenuation above 30 MHz = 20 dB.

Table 3. CLKOUT1 Frequency Ranges†

PLLFREQ3 (C13)	PLLFREQ2 (G11)	PLLFREQ1 (F11)	CLKOUT1 Frequency Range (MHz)
0	0	0	50–140
0	0	1	65–167
0	1	0	130–167

[†] Due to overlap of frequency ranges when choosing the PLLFREQ, more than one frequency range can contain the CLKOUT1 frequency. Choose the lowest frequency range that includes the desired frequency. For example, for CLKOUT1 = 133 MHz, choose PLLFREQ value of 000b. For CLKOUT1 = 167 MHz, choose PLLFREQ value of 001b. PLLFREQ values other than 000b, 001b, and 010b are reserved.

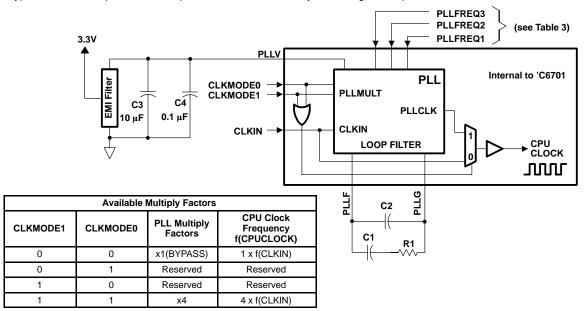


clock PLL (continued)

Table 4. 'C6701 PLL Component Selection Table

CLKMODE	CLKIN RANGE (MHz)	CPU CLOCK FREQUENCY (CLKOUT1) RANGE (MHz)	CLKOUT2 RANGE (MHz)	R1 (Ω)	C1 (nF)	C2 (pF)	TYPICAL LOCK TIME (μs)‡
x4	12.5-41.7	50–167	25-83.5	60.4	27	560	75

[‡] Under some operating conditions, the maximum PLL lock time may vary as much as 150% from the specified typical value. For example, if the typical lock time is specified as 100 μs, the maximum value may be as long as 250 μs.

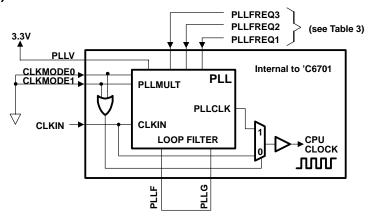


- NOTES: A. Keep the lead length and the number of vias between the PLLF pin, the PLLG pin, and R1, C1, and C2 to a minimum. In addition, place all PLL external components (R1, C1, C2, C3, C4, and the EMI Filter) as close to the 'C6000 device as possible. For the best performance, TI recommends that all the PLL external components be on a single side of the board without jumpers, switches, or components other than the ones shown.
 - B. For reduced PLL jitter, maximize the spacing between switching signals and the PLL external components (R1, C1, C2, C3, C4, and the EMI Filter).
 - C. The 3.3-V supply for the EMI filter must be from the same 3.3-V power plane supplying the I/O voltage, DV_{DD}.

Figure 5. External PLL Circuitry for Either PLL x4 Mode or x1 (Bypass) Mode



clock PLL (continued)



NOTES: A. For a system with ONLY PLL x1 (bypass) mode, short the PLLF terminal to the PLLG terminal.

B. The 3.3-V supply for the EMI filter must be from the same 3.3-V power plane supplying the I/O voltage, DVDD.

Figure 6. External PLL Circuitry for x1 (Bypass) Mode Only

power-supply sequencing

TI DSPs do not require specific power sequencing between the core supply and the I/O supply. However, systems should be designed to ensure that neither supply is powered up for extended periods of time if the other supply is below the proper operating voltage.

system-level design considerations

System-level design considerations, such as bus contention, may require supply sequencing to be implemented. In this case, the core supply should be powered up at the same time as, or prior to (and powered down after), the I/O buffers. This is to ensure that the I/O buffers receive valid inputs from the core before the output buffers are powered up, thus, preventing bus contention with other chips on the board.

power-supply design considerations

For systems using the C6000™ DSP platform of devices, the core supply may be required to provide in excess of 2 A per DSP until the I/O supply is powered up. This extra current condition is a result of uninitialized logic within the DSP(s) and is corrected once the CPU sees an internal clock pulse. With the PLL enabled, as the I/O supply is powered on, a clock pulse is produced stopping the extra current draw from the supply. With the PLL disabled, an external clock pulse may be required to stop this extra current draw. A normal current state returns once the I/O power supply is turned on and the CPU sees a clock pulse. Decreasing the amount of time between the core supply power up and the I/O supply power up can minimize the effects of this current draw.

A dual-power supply with simultaneous sequencing, such as available with TPS563xx controllers or PT69xx plug-in power modules, can be used to eliminate the delay between core and I/O power up [see the *Using the TPS56300 to Power DSPs* application report (literature number SLVA088)]. A Schottky diode can also be used to tie the core rail to the I/O rail, effectively pulling up the I/O power supply to a level that can help initialize the logic within the DSP.

Core and I/O supply voltage regulators should be located close to the DSP (or DSP array) to minimize inductance and resistance in the power delivery path. Additionally, when designing for high-performance applications utilizing the C6000TM platform of DSPs, the PC board should include separate power planes for core, I/O, and ground, all bypassed with high-quality low-ESL/ESR capacitors.



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absolute maximum ratings over operating case temperature range (unless otherwise noted)†

Supply voltage range, CV _{DD} (see Note 1)	
Supply voltage range, DV _{DD} (see Note 1)	0.3 V to 4 V
Input voltage range	0.3 V to 4 V
Output voltage range	0.3 V to 4 V
Operating case temperature range, T _C S suffix device	40°C to 90°C
W suffix device	
Storage temperature range, T _{sto}	55°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: All voltage values are with respect to VSS.

recommended operating conditions

			MIN	NOM	MAX	UNIT
CVDD	Supply voltage		1.81	1.9	1.99	V
DV_{DD}	Supply voltage		3.14	3.30	3.46	V
VSS	Supply ground		0	0	0	V
V_{IH}	High-level input voltage					V
V_{IL}	Low-level input voltage				8.0	V
ЮН	High-level output current				-12	mA
loL	Low-level output current				12	mA
То	Case temperature	S suffix device	-40		90	°C
T _C	W suffix device				115	C

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electrical characteristics over recommended ranges of supply voltage and operating case temperature (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Vон	High-level output voltage	$DV_{DD} = MIN, I_{OH} = MAX$	2.4			V
VOL	Low-level output voltage	$DV_{DD} = MIN, I_{OL} = MAX$			0.6	V
Iį	Input current [†]	$V_I = V_{SS}$ to DV_{DD}			±10	uA
loz	Off-state output current	$V_O = DV_{DD}$ or 0 V			±10	uA
I _{DD2V}	Supply current, CPU + CPU memory access‡	CV _{DD} = NOM, CPU clock = 150 MHz		470		mA
I _{DD2V}	Supply current, peripherals§	CV _{DD} = NOM, CPU clock = 150 MHz		250		mA
I _{DD3V}	Supply current, I/O pins¶	DV _{DD} = NOM, CPU clock = 150 MHz		85		mA
Ci	Input capacitance				*15	pF
Co	Output capacitance				*15	pF

^{*} This parameter is not tested.

TRST is not included due to internal pulldown.

[‡] Measured with average CPU activity:

50% of time: 8 instructions per cycle, 32-bit DMEM access per cycle 50% of time: 2 instructions per cycle, 16-bit DMEM access per cycle

§ Measured with average peripheral activity:

50% of time: Timers at max rate, McBSPs at E1 rate, and DMA burst transfer between DMEM and SDRAM

50% of time: Timers at max rate, McBSPs at E1 rate, and DMA servicing McBSPs

¶ Measured with average I/O activity (30-pF load, SDCLK on):

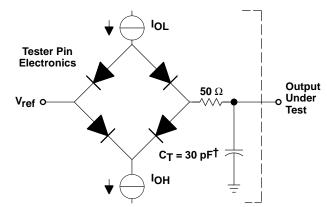
25% of time: Reads from external SDRAM Writes to external SDRAM

50% of time: No activity



[†]TMS and TDI are not included due to internal pullups.

PARAMETER MEASUREMENT INFORMATION



[†] Typical distributed load circuit capacitance.

signal-transition levels

All input and output timing parameters are referenced to 1.5 V for both "0" and "1" logic levels.

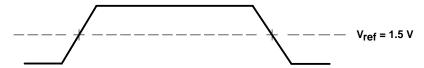


Figure 7. Input and Output Voltage Reference Levels for ac Timing Measurements

INPUT AND OUTPUT CLOCKS

timing requirements for CLKIN† (see Figure 8)

		'C6701-14			'C6701-16						
NO.			CLKMOI		CLKMODE = x4		CLKMODE = x4		CLKMOD	CLKMODE = x1	
			MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
1	tc(CLKIN)	Cycle time, CLKIN	28.4		7.1		24		6		ns
2	tw(CLKINH)	Pulse duration, CLKIN high	*0.4C [‡]		*0.45C [‡]		*0.4C [‡]		*0.45C [‡]		ns
3	tw(CLKINL)	Pulse duration, CLKIN low	*0.4C‡		*0.45C [‡]		*0.4C [‡]		*0.45C‡		ns
4	t _t (CLKIN)	Transition time, CLKIN		*5		*0.6		*5		*0.6	ns

[†] The reference points for the rise and fall transitions are measured at 20% and 80%, respectively, of V_{IH}.

^{*}This parameter is not tested.

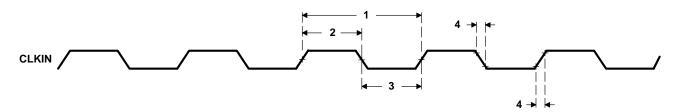


Figure 8. CLKIN Timings

switching characteristics for CLKOUT1^{‡§} (see Figure 9)

				'C670 'C670			
NO.	PARAMETER		CLKMODE = x4		CLKMODE = x1		UNIT
			MIN	MAX	MIN	MAX	
1	tc(CKO1)	Cycle time, CLKOUT1	*P - 0.7	*P + 0.7	*P - 0.7	*P + 0.7	ns
2	tw(CKO1H)	Pulse duration, CLKOUT1 high	*(P/2) - 0.5	*(P/2) + 0.5	*PH – 0.5	*PH + 0.5	ns
3	tw(CKO1L)	Pulse duration, CLKOUT1 low	*(P/2) - 0.5	*(P/2) + 0.5	*PL – 0.5	*PL + 0.5	ns
4	tt(CKO1)	Transition time, CLKOUT1		*0.6		*0.6	ns

 $[\]frac{1}{P} = \frac{1}{CPU}$ clock frequency in nanoseconds (ns).

^{*}This parameter is not tested.

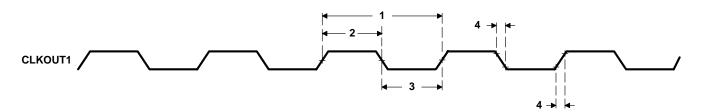


Figure 9. CLKOUT1 Timings



 $[\]ddagger$ C = CLKIN cycle time in ns. For example, when CLKIN frequency is 10 MHz, use C = 100 ns.

[§] PH is the high period of CLKIN in ns and PL is the low period of CLKIN in ns.

INPUT AND OUTPUT CLOCKS (CONTINUED)

switching characteristics for CLKOUT2[†] (see Figure 10)

NO.		PARAMETER	'C670 'C670		UNIT
			MIN	MAX	
1	tc(CKO2)	Cycle time, CLKOUT2	*2P – 0.7	*2P + 0.7	ns
2	tw(CKO2H)	Pulse duration, CLKOUT2 high	*P - 0.7	*P + 0.7	ns
3	tw(CKO2L)	Pulse duration, CLKOUT2 low	*P - 0.7	*P + 0.7	ns
4	tt(CKO2)	Transition time, CLKOUT2		*0.6	ns

 $[\]dagger P = 1/CPU$ clock frequency in ns.

^{*}This parameter is not tested.

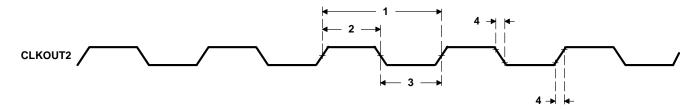


Figure 10. CLKOUT2 Timings

SDCLK, **SSCLK** timing parameters

SDCLK timing parameters are the same as CLKOUT2 parameters.

SSCLK timing parameters are the same as CLKOUT1 or CLKOUT2 parameters, depending on SSCLK configuration.

switching characteristics for the relation of SSCLK, SDCLK, and CLKOUT2 to CLKOUT1 (see Figure 11)

NO.		PARAMETER	'C670 'C670		UNIT
		MIN	MAX		
1	td(CKO1-SSCLK)	Delay time, CLKOUT1 edge to SSCLK edge	-0.8	3.4	ns
2	td(CKO1-SSCLK1/2)	Delay time, CLKOUT1 edge to SSCLK edge (1/2 clock rate)	-1.0	3.0	ns
3	td(CKO1-CKO2)	Delay time, CLKOUT1 edge to CLKOUT2 edge	-1.5	2.5	ns
4	td(CKO1-SDCLK)	Delay time, CLKOUT1 edge to SDCLK edge	-1.5	1.9	ns

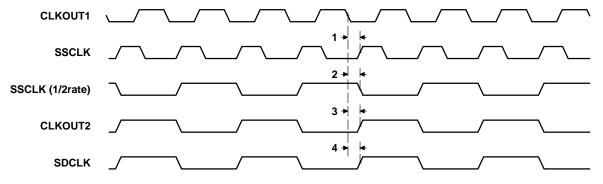


Figure 11. Relation of CLKOUT2, SDCLK, and SSCLK to CLKOUT1



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ASYNCHRONOUS MEMORY TIMING

timing requirements for asynchronous memory cycles[†] (see Figure 12 and Figure 13)

NO.			'C6701-14 'C6701-16		UNIT
			MIN	MAX	
6	t _{su} (EDV-CKO1H)	Setup time, read EDx valid before CLKOUT1 high	4.8		ns
7	th(CKO1H-EDV)	Hold time, read EDx valid after CLKOUT1 high	1.5		ns
10	t _{su} (ARDY-CKO1H)	Setup time, ARDY valid before CLKOUT1 high	3.5		ns
11	th(CKO1H-ARDY)	Hold time, ARDY valid after CLKOUT1 high	1.5		ns

[†] To ensure data setup time, simply program the strobe width wide enough. ARDY is internally synchronized. If ARDY does meet setup or hold time, it may be recognized in the current cycle or the next cycle. Thus, ARDY can be an asynchronous input.

switching characteristics for asynchronous memory cycles‡ (see Figure 12 and Figure 13)

NO.	PARAMETER		'C670	UNIT	
			MIN	MAX	
1	td(CKO1H-CEV)	Delay time, CLKOUT1 high to CEx valid	-1.0	4.5	ns
2	td(CKO1H-BEV)	Delay time, CLKOUT1 high to BEx valid		4.5	ns
3	td(CKO1H-BEIV)	Delay time, CLKOUT1 high to BEx invalid	-1.0		ns
4	td(CKO1H-EAV)	Delay time, CLKOUT1 high to EAx valid		4.5	ns
5	td(CKO1H-EAIV)	Delay time, CLKOUT1 high to EAx invalid	-1.0		ns
8	td(CKO1H-AOEV)	Delay time, CLKOUT1 high to AOE valid	-1.0	4.5	ns
9	td(CKO1H-AREV)	Delay time, CLKOUT1 high to ARE valid	-1.0	4.5	ns
12	td(CKO1H-EDV)	Delay time, CLKOUT1 high to EDx valid		4.5	ns
13	td(CKO1H-EDIV)	Delay time, CLKOUT1 high to EDx invalid	-1.0	•	ns
14	td(CKO1H-AWEV)	Delay time, CLKOUT1 high to AWE valid	-1.0	4.5	ns

[‡] The minimum delay is also the minimum output hold after CLKOUT1 high.



ASYNCHRONOUS MEMORY TIMING (CONTINUED)

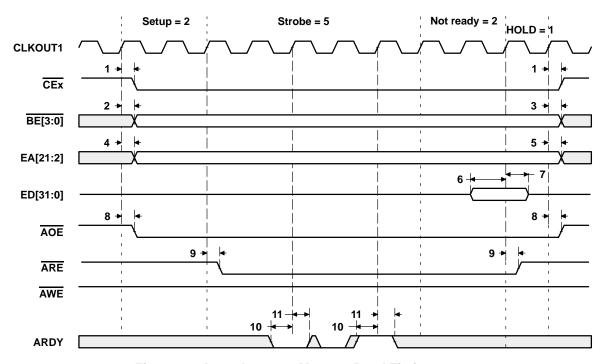


Figure 12. Asynchronous Memory Read Timing

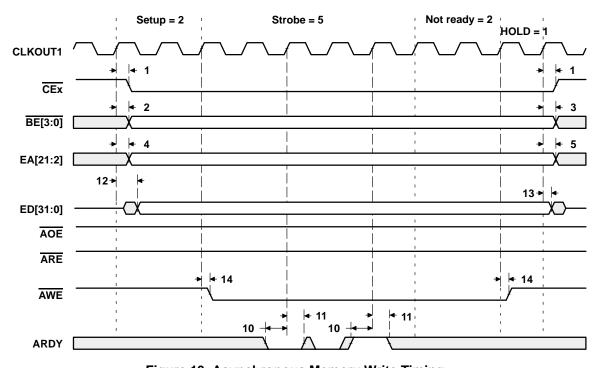


Figure 13. Asynchronous Memory Write Timing



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SYNCHRONOUS-BURST MEMORY TIMING

timing requirements for synchronous-burst SRAM cycles (full-rate SSCLK) (see Figure 14)

No	No.		'C6701-14		'C6701-16		
NO.			MIN	MAX	MIN	MAX	UNIT
7	t _{su} (EDV-SSCLKH)	Setup time, read EDx valid before SSCLK high	2.6		2.5		ns
8	th(SSCLKH-EDV)	Hold time, read EDx valid after SSCLK high	1.5		1.5		ns

switching characteristics for synchronous-burst SRAM cycles[†] (full-rate SSCLK) (see Figure 14 and Figure 15)

	24244555	'C6701-14		'C6701-16			
NO.	PARAMETER		MIN	MAX	MIN	MAX	UNIT
1	tosu(CEV-SSCLKH)	Output setup time, CEx valid before SSCLK high	0.5P - 1.5		0.5P - 1.3		ns
2	toh(SSCLKH-CEV)	Output hold time, CEx valid after SSCLK high	0.5P - 2.5		0.5P - 2.3		ns
3	tosu(BEV-SSCLKH)	Output setup time, BEx valid before SSCLK high	0.5P - 1.6		0.5P - 1.6		ns
4	toh(SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	0.5P - 2.5		0.5P - 2.3		ns
5	tosu(EAV-SSCLKH)	Output setup time, EAx valid before SSCLK high	0.5P - 1.7		0.5P - 1.7		ns
6	toh(SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	0.5P - 2.5		0.5P - 2.5		ns
9	tosu(ADSV-SSCLKH)	Output setup time, SSADS valid before SSCLK high	0.5P - 1.5		0.5P - 1.3		ns
10	toh(SSCLKH-ADSV)	Output hold time, SSADS valid after SSCLK high	0.5P - 2.5		0.5P - 2.3		ns
11	tosu(OEV-SSCLKH)	Output setup time, SSOE valid before SSCLK high	0.5P - 1.5		0.5P - 1.3		ns
12	toh(SSCLKH-OEV)	Output hold time, SSOE valid after SSCLK high	0.5P - 2.5		0.5P - 2.5		ns
13	tosu(EDV-SSCLKH)	Output setup time, EDx valid before SSCLK high	0.5P - 1.5		0.5P - 1.3		ns
14	toh(SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	0.5P - 2.5		0.5P - 2.5		ns
15	tosu(WEV-SSCLKH)	Output setup time, SSWE valid before SSCLK high	0.5P - 1.5		0.5P - 1.3		ns
16	toh(SSCLKH-WEV)	Output hold time, SSWE valid after SSCLK high	0.5P - 2.5		0.5P - 2.3		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter.

When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

For CLKMODE x1, 0.5P is defined as PH (pulse duration of CLKIN high) for all output setup times; 0.5P is defined as PL (pulse duration of CLKIN low) for all output hold times.



SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

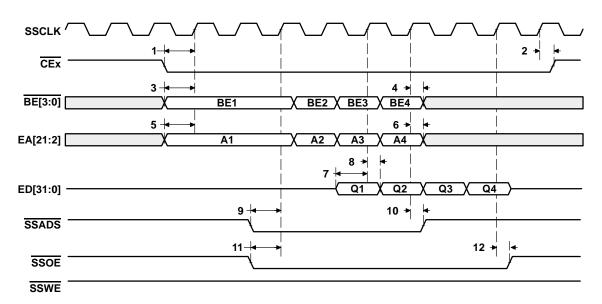


Figure 14. SBSRAM Read Timing (Full-Rate SSCLK)

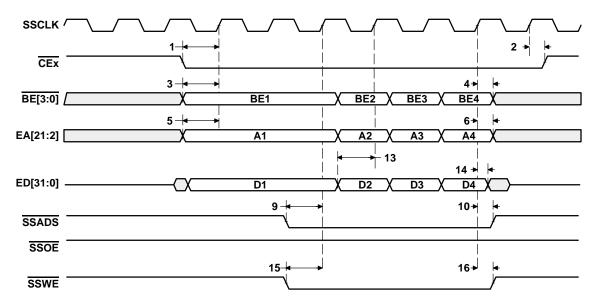


Figure 15. SBSRAM Write Timing (Full-Rate SSCLK)

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SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

timing requirements for synchronous-burst SRAM cycles (half-rate SSCLK) (see Figure 16)

NO.		'C670	'C6701-14		'C6701-16	
NO.		MIN	MAX	MIN	MAX	UNIT
7	tsu(EDV-SSCLKH) Setup time, read EDx valid before SSCLK high	3.8		3.8		ns
8	th(SSCLKH-EDV) Hold time, read EDx valid after SSCLK high	1.5		1.5		ns

switching characteristics for synchronous-burst SRAM cycles[†] (half-rate SSCLK) (see Figure 16 and Figure 17)

NO.	DADAMETED	'C6701-14		'C6701-16			
	PARAMETER		MIN	MAX	MIN	MAX	UNIT
1	tosu(CEV-SSCLKH)	Output setup time, CEx valid before SSCLK high	1.5P - 5.5		1.5P - 4.5		ns
2	toh(SSCLKH-CEV)	Output hold time, CEx valid after SSCLK high	0.5P - 2.3		0.5P - 2		ns
3	tosu(BEV-SSCLKH)	Output setup time, BEx valid before SSCLK high	1.5P - 5.5		1.5P - 4.5		ns
4	toh(SSCLKH-BEIV)	Output hold time, BEx invalid after SSCLK high	0.5P - 2.3		0.5P - 2		ns
5	tosu(EAV-SSCLKH)	Output setup time, EAx valid before SSCLK high	1.5P - 5.5		1.5P - 4.5		ns
6	toh(SSCLKH-EAIV)	Output hold time, EAx invalid after SSCLK high	0.5P - 2.3		0.5P - 2		ns
9	tosu(ADSV-SSCLKH)	Output setup time, SSADS valid before SSCLK high	1.5P - 5.5		1.5P - 4.5		ns
10	toh(SSCLKH-ADSV)	Output hold time, SSADS valid after SSCLK high	0.5P - 2.3		0.5P - 2		ns
11	tosu(OEV-SSCLKH)	Output setup time, SSOE valid before SSCLK high	1.5P - 5.5		1.5P - 4.5		ns
12	toh(SSCLKH-OEV)	Output hold time, SSOE valid after SSCLK high	0.5P - 2.3		0.5P - 2		ns
13	tosu(EDV-SSCLKH)	Output setup time, EDx valid before SSCLK high	1.5P - 5.5		1.5P - 4.5		ns
14	toh(SSCLKH-EDIV)	Output hold time, EDx invalid after SSCLK high	0.5P - 2.3		0.5P - 2.2		ns
15	tosu(WEV-SSCLKH)	Output setup time, SSWE valid before SSCLK high	1.5P - 5.5		1.5P - 4.5		ns
16	toh(SSCLKH-WEV)	Output hold time, SSWE valid after SSCLK high	0.5P - 2.3		0.5P - 2		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns. For CLKMODE x1:



^{1.5}P = P + PH, where P = 1/CPU clock frequency, and PH = pulse duration of CLKIN high.

^{0.5}P = PL, where PL = pulse duration of CLKIN low.

SYNCHRONOUS-BURST MEMORY TIMING (CONTINUED)

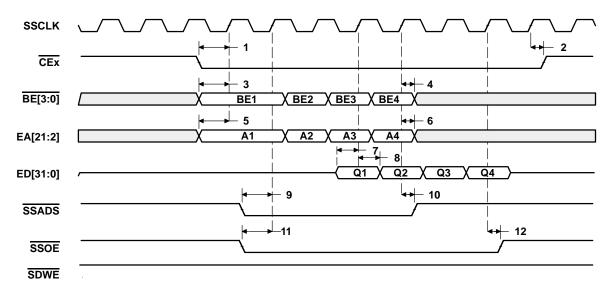


Figure 16. SBSRAM Read Timing (1/2 Rate SSCLK)

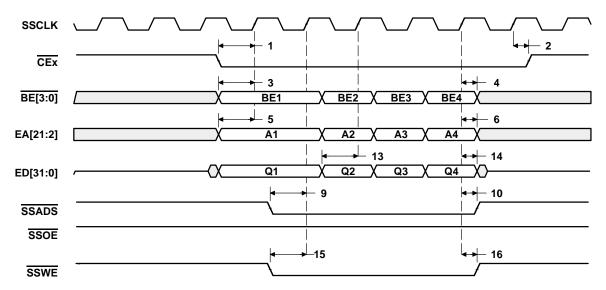


Figure 17. SBSRAM Write Timing (1/2 Rate SSCLK)

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SYNCHRONOUS DRAM TIMING

timing requirements for synchronous DRAM cycles (see Figure 18)

NO	NO		'C6701-16	
NO.		MIN MAX	MIN MAX	UNIT
7	t _{su(EDV-SDCLKH)} Setup time, read EDx valid before SDCLK high	2	2	ns
8	th(SDCLKH-EDV) Hold time, read EDx valid after SDCLK high	3	3	ns

switching characteristics for synchronous DRAM cycles[†] (see Figure 18–Figure 23)

No.		DADAMETED	'C6701-	14	'C6701-	16	
NO.		PARAMETER		MAX	MIN	MAX	UNIT
1	tosu(CEV-SDCLKH)	Output setup time, CEx valid before SDCLK high	1.5P – 5		1.5P – 4		ns
2	toh(SDCLKH-CEV)	Output hold time, CEx valid after SDCLK high	0.5P - 1.9		0.5P - 1.5		ns
3	tosu(BEV-SDCLKH)	Output setup time, BEx valid before SDCLK high	1.5P – 5		1.5P – 4		ns
4	toh(SDCLKH-BEIV)	Output hold time, BEx invalid after SDCLK high	0.5P - 1.9		0.5P - 1.5		ns
5	tosu(EAV-SDCLKH)	Output setup time, EAx valid before SDCLK high	1.5P – 5		1.5P – 4		ns
6	toh(SDCLKH-EAIV)	Output hold time, EAx invalid after SDCLK high	0.5P - 1.9		0.5P - 1.5		ns
9	tosu(SDCAS-SDCLKH)	Output setup time, SDCAS valid before SDCLK high	1.5P – 5		1.5P – 4		ns
10	toh(SDCLKH-SDCAS)	Output hold time, SDCAS valid after SDCLK high	0.5P - 1.9		0.5P - 1.5		ns
11	tosu(EDV-SDCLKH)	Output setup time, EDx valid before SDCLK high	1.5P – 5		1.5P – 4		ns
12	toh(SDCLKH-EDIV)	Output hold time, EDx invalid after SDCLK high	0.5P - 1.9		0.5P - 1.5		ns
13	tosu(SDWE-SDCLKH)	Output setup time, SDWE valid before SDCLK high	1.5P – 5		1.5P – 4		ns
14	toh(SDCLKH-SDWE)	Output hold time, SDWE valid after SDCLK high	0.5P - 1.9		0.5P - 1.5		ns
15	tosu(SDA10V-SDCLKH)	Output setup time, SDA10 valid before SDCLK high	1.5P – 5		1.5P – 4		ns
16	^t oh(SDCLKH-SDA10IV)	Output hold time, SDA10 invalid after SDCLK high	0.5P - 1.9		0.5P - 1.5		ns
17	tosu(SDRAS-SDCLKH)	Output setup time, SDRAS valid before SDCLK high	1.5P – 5		1.5P – 4		ns
18	toh(SDCLKH-SDRAS)	Output hold time, SDRAS valid after SDCLK high	0.5P - 1.9	•	0.5P - 1.5		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. When the PLL is used (CLKMODE x4), P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns. For CLKMODE x1:



^{1.5}P = P + PH, where P = 1/CPU clock frequency, and PH = pulse duration of CLKIN high.

^{0.5}P = PL, where PL = pulse duration of CLKIN low.

SYNCHRONOUS DRAM TIMING (CONTINUED)

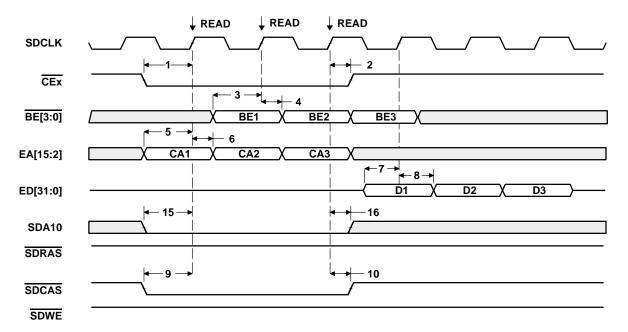


Figure 18. Three SDRAM Read Commands

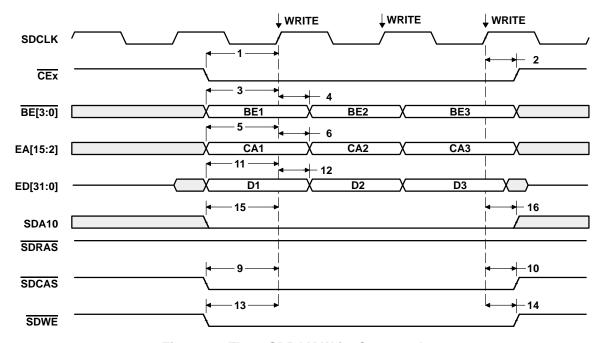


Figure 19. Three SDRAM Write Commands

SYNCHRONOUS DRAM TIMING (CONTINUED)

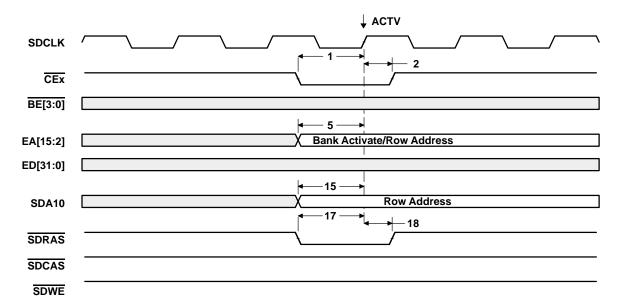


Figure 20. SDRAM ACTV Command

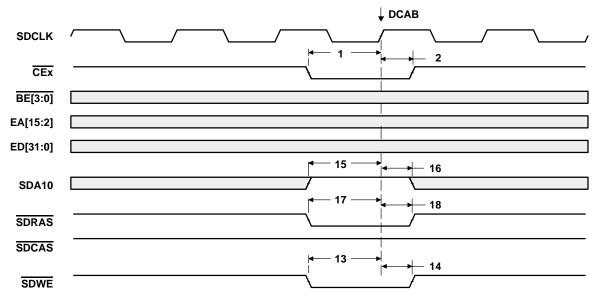


Figure 21. SDRAM DCAB Command



SYNCHRONOUS DRAM TIMING (CONTINUED)

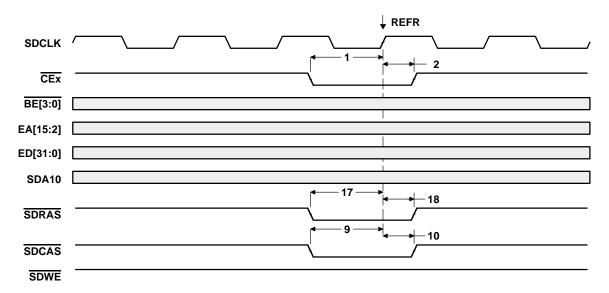


Figure 22. SDRAM REFR Command

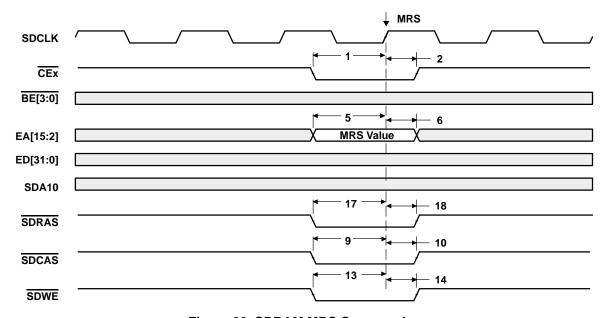


Figure 23. SDRAM MRS Command

HOLD/HOLDA TIMING

timing requirements for the hold/hold acknowledge cycles[†] (see Figure 24)

NO.			'C670 'C670	UNIT	
			MIN	MAX	
1	t _{su} (HOLDH-CKO1H)	Setup time, HOLD high before CLKOUT1 high	5		ns
2	th(CKO1H-HOLDL)	Hold time, HOLD low after CLKOUT1 high	2		ns

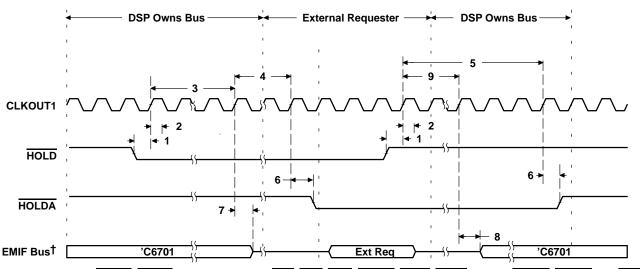
[†] HOLD is synchronized internally. Therefore, if setup and hold times are not met, it will either be recognized in the current cycle or in the next cycle. Thus, HOLD can be an asynchronous input.

switching characteristics for the hold/hold acknowledge cycles[‡] (see Figure 24)

NO.	PARAMETER		'C670 'C670		UNIT
			MIN	MAX	
3	[†] R(HOLDL-EMHZ)	Response time, HOLD low to EMIF high impedance	4P	§	ns
4	[†] R(EMHZ-HOLDAL)	Response time, EMIF high impedance to HOLDA low		2P	ns
5	[†] R(HOLDH-HOLDAH)	Response time, HOLD high to HOLDA high	4P	7P	ns
6	td(CKO1H-HOLDAL)	Delay time, CLKOUT1 high to HOLDA valid	1	8	ns
7	td(CKO1H-BHZ)	Delay time, CLKOUT1 high to EMIF Bus high impedance¶	*1	*8	ns
8	td(CKO1H-BLZ)	Delay time, CLKOUT1 high to EMIF Bus low impedance¶	*1	*12	ns
9	[†] R(HOLDH-BLZ)	Response time, HOLD high to EMIF Bus low impedance¶	3P	6P	ns

 $[\]ddagger$ P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

[¶]EMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.
*This parameter is not tested.



† EMIF Bus consists of CE[3:0], BE[3:0], ED[31:0], EA[21:2], ARE, AOE, AWE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, and SDWE.

Figure 24. HOLD/HOLDA Timing



[§] All pending EMIF transactions are allowed to complete before HOLDA is asserted. The worst cases for this is an asynchronous read or write with external ARDY used or a minimum of eight consecutive SDRAM reads or writes when RBTR8 = 1. If no bus transactions are occurring, then the minimum delay time can be achieved. Also, bus hold can be indefinitely delayed by setting the NOHOLD = 1.

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RESET TIMING

timing requirements for reset (see Figure 25)

NO.			'C6701-14 'C6701-16		UNIT
			MIN	IIN MAX	
1	1 t _{w(RESET)}	Width of the RESET pulse (PLL stable) [†]	*10		CLKOUT1 cycles
		Width of the RESET pulse (PLL needs to sync up)‡	*250		μs

[†] This parameter applies to CLKMODE x1 when CLKIN is stable and applies to CLKMODE x4 when CLKIN and PLL are stable.

switching characteristics during reset§ (see Figure 25)

NO.		PARAMETER		1-14 1-16	UNIT
		MIN	MAX		
2	^t R(RESET)	Response time to change of value in RESET signal	*1		CLKOUT1 cycles
3	td(CKO1H-CKO2IV)	Delay time, CLKOUT1 high to CLKOUT2 invalid	*-1		ns
4	td(CKO1H-CKO2V)	Delay time, CLKOUT1 high to CLKOUT2 valid		*10	ns
5	td(CKO1H-SDCLKIV)	Delay time, CLKOUT1 high to SDCLK invalid	*-1		ns
6	td(CKO1H-SDCLKV)	Delay time, CLKOUT1 high to SDCLK valid		*10	ns
7	td(CKO1H-SSCKIV)	Delay time, CLKOUT1 high to SSCLK invalid	*-1		ns
8	td(CKO1H-SSCKV)	Delay time, CLKOUT1 high to SSCLK valid		*10	ns
9	td(CKO1H-LOWIV)	Delay time, CLKOUT1 high to low group invalid	*-1		ns
10	td(CKO1H-LOWV)	Delay time, CLKOUT1 high to low group valid		*10	ns
11	td(CKO1H-HIGHIV)	Delay time, CLKOUT1 high to high group invalid	*-1		ns
12	td(CKO1H-HIGHV)	Delay time, CLKOUT1 high to high group valid		*10	ns
13	td(CKO1H-ZHZ)	Delay time, CLKOUT1 high to Z group high impedance	*-1		ns
14	td(CKO1H-ZV)	Delay time, CLKOUT1 high to Z group valid		*10	ns

[§] Low group consists of: High group consists of:

IACK, INUM[3:0], DMAC[3:0], PD, TOUT0, and TOUT1.

HRDY and HINT.

Z group consists of:

<u>EA[21:2]</u>, ED[31:0], CE[3:0], BE[3:0], ARE, AWE, AOE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, SDWE, HD[15:0], CLKX0, CLKX1, FSX0, FSX1, DX0, DX1, CLKR0, CLKR1, FSR0, and FSR1.

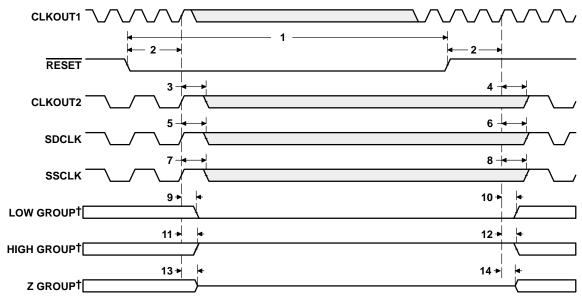


^{*}This parameter is not tested.

[‡] This parameter only applies to CLKMODE x4. The RESET signal is not connected internally to the clock PLL circuit. The PLL, however, may need up to 250 µs to stabilize following device powerup or after PLL configuration has been changed. During that time, RESET must be asserted to ensure proper device operation. See the *clock PLL* section for PLL lock times.

^{*}This parameter is not tested.

RESET TIMING (CONTINUED)



† Low group consists of: High group consists of: Z group consists of: IACK, INUM[3:0], DMAC[3:0], PD, TOUT0, and TOUT1.

HRDY and HINT.

EA[21:2], ED[31:0], CE[3:0], BE[3:0], ARE, AWE, AOE, SSADS, SSOE, SSWE, SDA10, SDRAS, SDCAS, SDWE, HD[15:0], CLKX0, CLKX1, FSX0, FSX1, DX0, DX1, CLKR0, CLKR1, FSR0, and FSR1.

Figure 25. Reset Timing



EXTERNAL INTERRUPT/RESET TIMING

timing requirements for interrupt response cycles^{†‡} (see Figure 26)

NO.		'C6701-14 'C6701-16	UNIT
		MIN MAX	
2	t _W (ILOW) Width of the interrupt pulse low	*2P	ns
3	t _w (IHIGH) Width of the interrupt pulse high	*2P	ns

[†] Interrupt signals are synchronized internally and are potentially recognized one cycle later if setup and hold times are violated. Thus, they can be connected to asynchronous inputs.

switching characteristics during interrupt response cycles§ (see Figure 26)

NO.		PARAMETER		701-14 701-16	UNIT
			MIN	MAX	
1	tR(EINTH-IACKH)	Response time, EXT_INTx high to IACK high	9P		ns
4	td(CKO2L-IACKV)	Delay time, CLKOUT2 low to IACK valid	-0.5P	13 – 0.5P	ns
5	td(CKO2L-INUMV)	Delay time, CLKOUT2 low to INUMx valid		10 – 0.5P	ns
6	td(CKO2L-INUMIV)	Delay time, CLKOUT2 low to INUMx invalid	-0.5P		ns

 $[\]five P$ = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns. When the PLL is used (CLKMODE x4), 0.5P = 1/(2 × CPU clock frequency). For CLKMODE x1: 0.5P = PH, where PH is the high period of CLKIN.

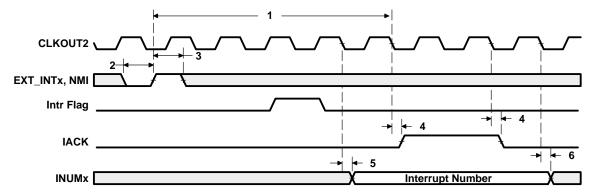


Figure 26. Interrupt Timing

 $^{^\}ddagger$ P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

^{*}This parameter is not tested.

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HOST-PORT INTERFACE TIMING

timing requirements for host-port interface cycles^{†‡} (see Figure 27, Figure 28, Figure 29, and Figure 30)

NO.				01-14 01-16	UNIT
			MIN	MAX	
1	t _{su(SEL-HSTBL)}	Setup time, select signals§ valid before HSTROBE low	4		ns
2	th(HSTBL-SEL)	Hold time, select signals valid after HSTROBE low	2		ns
3	tw(HSTBL)	Pulse duration, HSTROBE low	*2P		ns
4	tw(HSTBH)	Pulse duration, HSTROBE high between consecutive accesses	*2P		ns
10	t _{su(SEL-HASL)}	Setup time, select signals§ valid before HAS low	4		ns
11	th(HASL-SEL)	Hold time, select signals§ valid after HAS low	2		ns
12	t _{su(HDV-HSTBH)}	Setup time, host data valid before HSTROBE high	3		ns
13	th(HSTBH-HDV)	Hold time, host data valid after HSTROBE high	2		ns
14	^t h(HRDYL-HSTBL)	Hold time, HSTROBE low after HRDY low. HSTROBE should not be inactivated until HRDY is active (low); otherwise, HPI writes will not complete properly.	*1		ns
18	t _{su(HASL-HSTBL)}	Setup time, HAS low before HSTROBE low	*2		ns
19	th(HSTBL-HASL)	Hold time, HAS low after HSTROBE low	*2		ns

^{*}This parameter is not tested.

switching characteristics during host-port interface cycles^{†‡} (see Figure 27, Figure 28, Figure 29, and Figure 30)

NO.	PARAMETER		'C670 'C670	UNIT	
		MIN	MAX		
5	td(HCS-HRDY)	Delay time, HCS to HRDY¶	1	12	ns
6	td(HSTBL-HRDYH)	Delay time, HSTROBE low to HRDY high#	1	12	ns
7	toh(HSTBL-HDLZ)	Output hold time, HD low impedance after HSTROBE low for an HPI read	*4		ns
8	td(HDV-HRDYL)	Delay time, HD valid to HRDY low	*P - 3	*P + 3	ns
9	toh(HSTBH-HDV)	Output hold time, HD valid after HSTROBE high	3	12	ns
15	td(HSTBH-HDHZ)	Delay time, HSTROBE high to HD high impedance	*3	*12	ns
16	td(HSTBL-HDV)	Delay time, HSTROBE low to HD valid	3	12	ns
17	td(HSTBH-HRDYH)	Delay time, HSTROBE high to HRDY high	1	12	ns

^{*}This parameter is not tested.

This parameter is used after the second half-word of an HPID write or autoincrement read. HRDY remains low if the access is not an HPID write or autoincrement read. Reading or writing to HPIC or HPIA does not affect the HRDY signal.



[†] HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2; INOT(HDS1 XOR HDS2)] OR HCS.

[‡] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

[§] Select signals include: HCNTRL[1:0], HR/W, and HHWIL.

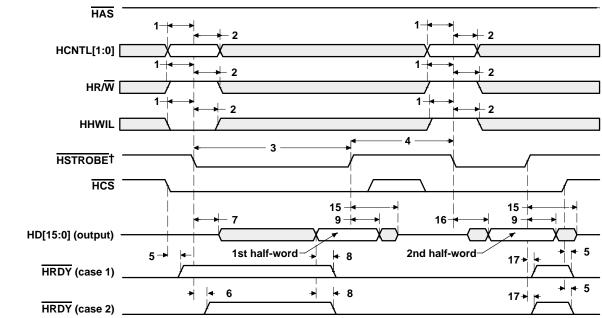
[†] HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

[‡] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

[¶]HCS enables HRDY, and HRDY is always low when HCS is high. The case where HRDY goes high when HCS falls indicates that HPI is busy completing a previous HPID write or READ with autoincrement.

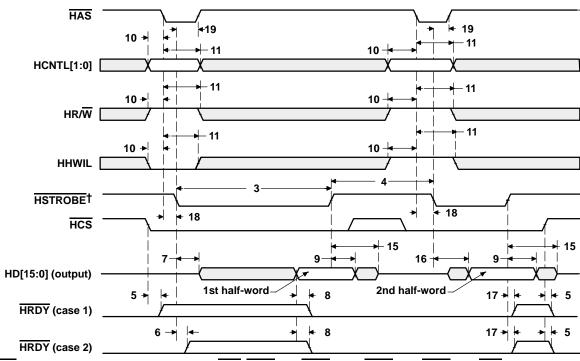
[#] This parameter is used during an HPID read. At the beginning of the first half-word transfer on the falling edge of HSTROBE, the HPI sends the request to the DMA auxiliary channel, and HRDY remains high until the DMA auxiliary channel loads the requested data into HPID.

HOST-PORT INTERFACE TIMING (CONTINUED)



† HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 27. HPI Read Timing (HAS Not Used, Tied High)

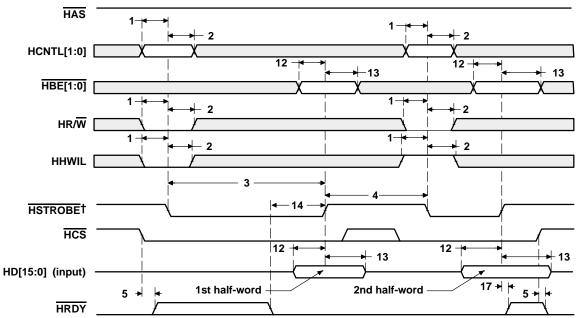


† HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 28. HPI Read Timing (HAS Used)

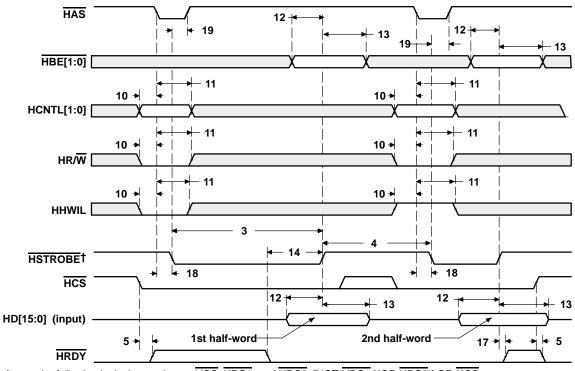


HOST-PORT INTERFACE TIMING (CONTINUED)



† HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 29. HPI Write Timing (HAS Not Used, Tied High)



[†] HSTROBE refers to the following logical operation on HCS, HDS1, and HDS2: [NOT(HDS1 XOR HDS2)] OR HCS.

Figure 30. HPI Write Timing (HAS Used)



MULTICHANNEL BUFFERED SERIAL PORT TIMING

timing requirements for McBSP^{†‡} (see Figure 31)

NO.				'C670 'C670		UNIT
				MIN	MAX	
2	t _C (CKRX)	Cycle time, CLKR/X	CLKR/X ext	*2P		ns
3	tw(CKRX)	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X ext	*P – 1		ns
5		L CKPL) Setup time, external FSR high before CLKR low	CLKR int	*13		
5	5 t _{su(FRH-CKRL)}		CLKR ext	4		ns
		Held the end of EOD bight of the OHAD lead	CLKR int	*7		
6	th(CKRL-FRH)	Hold time, external FSR high after CLKR low	CLKR ext	4		ns
_		Octor the DD callet a few OLKD less	CLKR int	10		
7	tsu(DRV-CKRL)	Setup time, DR valid before CLKR low	CLKR ext	1		ns
		HILLS BROWN A CHARL	CLKR int	4		
8	th(CKRL-DRV)	Hold time, DR valid after CLKR low	CLKR ext	4		ns
40		Octor Conservational FOV bight before OHAV loss	CLKX int	*13		
10	^t su(FXH-CKXL)	XH-CKXL) Setup time, external FSX high before CLKX low	CLKX ext	4		ns
44		CKVL EVID. Hold time external FSX high after CLKX low	CLKX int	*7		
11	th(CKXL-FXH)		CLKX ext	3		ns

 $[\]dagger$ P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.



[‡] CLKRP = CLKXP = FSRP = FSXP = 0 in the pin control register (PCR). If polarity of any of the signals is inverted, then the timing references of that signal are also inverted.

^{*}This parameter is not tested.

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MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

switching characteristics for McBSP^{†‡§} (see Figure 31)

NO.	PARAMETER				1-14 1-16	UNIT
					MAX	
1	td(CKSH-CKRXH)	Delay time, CLKS high to CLKR/X high for internal CLKR/X generated from CLKS input		3	15	ns
2	t _C (CKRX)	Cycle time, CLKR/X	CLKR/X int	2P		ns
3	tw(CKRX)	Pulse duration, CLKR/X high or CLKR/X low	CLKR/X int	C – 1¶	C + 1¶	ns
4	td(CKRH-FRV)	Delay time, CLKR high to internal FSR valid	CLKR int	-4	4	ns
_	^t d(CKXH-FXV)	(CKXH-FXV) Delay time, CLKX high to internal FSX valid	CLKX int	-4	5	
9			CLKX ext	*3	*16	ns
40		Disable time, DX high impedance following last data bit from	CLKX int	*-3	*2	
12	^t dis(CKXH-DXHZ)	CLKX high	CLKX ext	*2	*9	ns
40		B. C. OHWILL BY III	CLKX int	-2	4	
13	td(CKXH-DXV)	Delay time, CLKX high to DX valid.	CLKX ext	3	16	ns
	1.	Delay time, FSX high to DX valid.	FSX int	*-2	*4	
14	^t d(FXH-DXV)	ONLY applies when in data delay 0 (XDATDLY = 00b) mode.	FSX ext	*2	*10	ns

[†] CLKRP = CLKXP = FSRP = FSXP = 0 in the pin control register (PCR). If polarity of any of the signals is inverted, then the timing references of that signal are also inverted.

S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

= sample rate generator input clock = P_clks if CLKSM = 0 (P_clks = CLKS period)

H = CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

[‡] Minimum delay times also represent minimum output hold times.

 $[\]S P = 1/CPU$ clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

 $^{^{\}P}C = HorL$

^{*}This parameter is not tested.

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

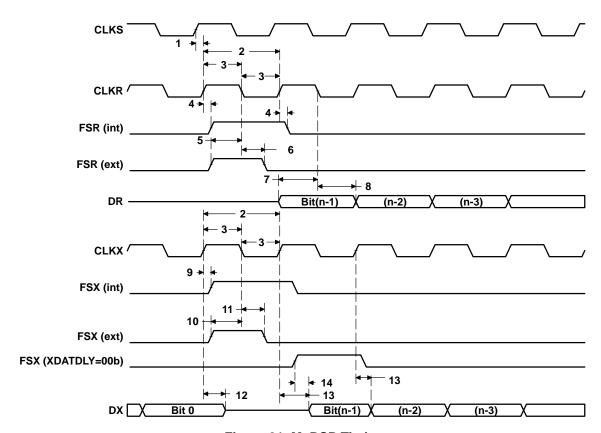


Figure 31. McBSP Timings

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MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for FSR when GSYNC = 1 (see Figure 32)

NO.	o		'C6701-14 'C6701-16	
		MIN	MAX	
1	t _{su(FRH-CKSH)} Setup time, FSR high before CLKS high	*4		ns
2	th(CKSH-FRH) Hold time, FSR high after CLKS high	*4		ns

^{*}This parameter is not tested.

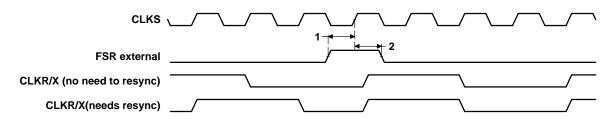


Figure 32. FSR Timing When GSYNC = 1

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = $0^{\dagger \ddagger}$ (see Figure 33)

	NO.		'C6701-14 'C6701-16			
NO.		MASTER SLAVE			VΕ	UNIT
		MIN	MAX	MIN	MAX	
4	t _{SU(DRV-CKXL)} Setup time, DR valid before CLKX low	12		2 – 3P		ns
5	th(CKXL-DRV) Hold time, DR valid after CLKX low	4		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 0^{+1} (see Figure 33)

	DADAMETED						
NO.		PARAMETER		TER§	SL	AVE	UNIT
			MIN	MAX	MIN	MAX	
1	th(CKXL-FXL)	Hold time, FSX low after CLKX low¶	T – 4	T + 4			ns
2	td(FXL-CKXH)	Delay time, FSX low to CLKX high#	L – 4	L + 4			ns
3	td(CKXH-DXV)	Delay time, CLKX high to DX valid	-4	4	3P + 1	5P + 17	ns
6	tdis(CKXL-DXHZ)	Disable time, DX high impedance following last data bit from CLKX low	*L – 2	*L + 3			ns
7	tdis(FXH-DXHZ)	Disable time, DX high impedance following last data bit from FSX high			*P + 4	*3P + 17	ns
8	td(FXL-DXV)	Delay time, FSX low to DX valid			2P + 1	4P + 13	ns

^{*}This parameter is not tested.

T = CLKX period = (1 + CLKGDV) * S

H = CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP



[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[§] S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

⁼ sample rate generator input clock = P_clks if CLKSM = 0 (P_clks = CLKS period)

[¶] FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

[#]FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

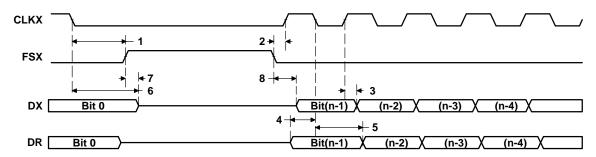


Figure 33. McBSP Timing as SPI Master or Slave: CLKSTP = 10b, CLKXP = 0

timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = $0^{+\ddagger}$ (see Figure 34)

	NO.		'C6701-14 'C6701-16			
NO.			ER	SLAVE		UNIT
		MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXH)} Setup time, DR valid before CLKX high	12		2 – 3P		ns
5	th(CKXH-DRV) Hold time, DR valid after CLKX high	4		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.



[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 0^{+1} (see Figure 34)

NO.					01-14 01-16		
		PARAMETER	MAST	ER§	SL	AVE	UNIT
			MIN	MAX	MIN	MAX	
1	th(CKXL-FXL)	Hold time, FSX low after CLKX low¶	L – 4	L + 4			ns
2	td(FXL-CKXH)	Delay time, FSX low to CLKX high#	T – 4	T + 4			ns
3	td(CKXL-DXV)	Delay time, CLKX low to DX valid	-4	4	3P + 1	5P + 17	ns
6	tdis(CKXL-DXHZ)	Disable time, DX high impedance following last data bit from CLKX low	*-2	*4	*3P + 4	*5P + 17	ns
7	td(FXL-DXV)	Delay time, FSX low to DX valid	*H – 2	*H + 3	2P + 1	4P + 13	ns

^{*}This parameter is not tested.

H = CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

[#]FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

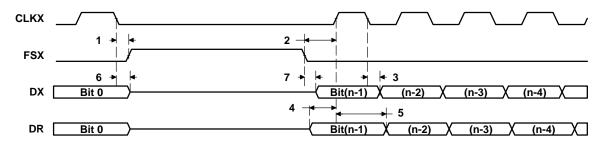


Figure 34. McBSP Timing as SPI Master or Slave: CLKSTP = 11b, CLKXP = 0



[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[§]S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

⁼ sample rate generator input clock = P_clks if CLKSM = 0 (P_clks = CLKS period)

T = CLKX period = (1 + CLKGDV) * S

[¶] FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

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MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

timing requirements for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1^{†‡} (see Figure 35)

	NO.		'C6701-14 'C6701-16			
NO.			ER	SLAV	UNIT	
			MAX	MIN	MAX	
4	t _{SU(DRV-CKXH)} Setup time, DR valid before CLKX high	12		2 – 3P		ns
5	th(CKXH-DRV) Hold time, DR valid after CLKX high	4		5 + 6P		ns

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

switching characteristics for McBSP as SPI master or slave: CLKSTP = 10b, CLKXP = 1^{+} (see Figure 35)

NO.		PARAMETER	MAST	ER§	SL	AVE	UNIT
			MIN	MAX	MIN	MAX	
1	th(CKXH-FXL)	Hold time, FSX low after CLKX high¶	T – 4	T + 4			ns
2	td(FXL-CKXL)	Delay time, FSX low to CLKX low#	H – 4	H + 4			ns
3	td(CKXL-DXV)	Delay time, CLKX low to DX valid	-4	4	3P + 1	5P + 17	ns
6	tdis(CKXH-DXHZ)	Disable time, DX high impedance following last data bit from CLKX high	*H – 2	*H + 3			ns
7	^t dis(FXH-DXHZ)	Disable time, DX high impedance following last data bit from FSX high		·	*P + 4	*3P + 17	ns
8	td(FXL-DXV)	Delay time, FSX low to DX valid			2P + 1	4P + 13	ns

^{*}This parameter is not tested.

T = CLKX period = (1 + CLKGDV) * S

H = CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP



[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[§]S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

⁼ sample rate generator input clock = P_clks if CLKSM = 0 (P_clks = CLKS period)

[¶] FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

[#]FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

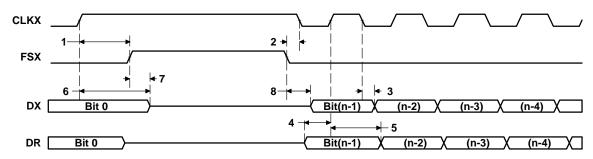


Figure 35. McBSP Timing as SPI Master or Slave: CLKSTP = 10b, CLKXP = 1

timing requirements for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1^{†‡} (see Figure 36)

			'C670 'C670			
NO.		MAST	ΓER	SLA	VΕ	UNIT
		MIN	MAX	MIN	MAX	
4	t _{su(DRV-CKXL)} Setup time, DR valid before CLKX low	12		2 – 3P		ns
5	th(CKXL-DRV) Hold time, DR valid after CLKX low	4	•	5 + 6P		ns

The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.



[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

MULTICHANNEL BUFFERED SERIAL PORT TIMING (CONTINUED)

switching characteristics for McBSP as SPI master or slave: CLKSTP = 11b, CLKXP = 1^{†‡} (see Figure 36)

NO.					5701-14 5701-16		
		PARAMETER	MAS	TER§	SL	AVE	UNIT
			MIN	MAX	MIN	MAX	
1	th(CKXH-FXL)	Hold time, FSX low after CLKX high¶	H – 4	H + 4			ns
2	td(FXL-CKXL)	Delay time, FSX low to CLKX low#	T – 4	T + 4			ns
3	td(CKXH-DXV)	Delay time, CLKX high to DX valid	-4	4	3P + 1	5P + 17	ns
6	tdis(CKXH-DXHZ)	Disable time, DX high impedance following last data bit from CLKX high	*-2	*4	*3P + 4	*5P + 17	ns
7	td(FXL-DXV)	Delay time, FSX low to DX valid	*L – 2	*L + 3	2P + 1	4P + 13	ns

^{*}This parameter is not tested.

T = CLKX period = (1 + CLKGDV) * S

H = CLKX high pulse width = (CLKGDV/2 + 1) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

L = CLKX low pulse width = (CLKGDV/2) * S if CLKGDV is even

= (CLKGDV + 1)/2 * S if CLKGDV is odd or zero

CLKXM = FSXM = 1, CLKRM = FSRM = 0 for master McBSP

CLKXM = CLKRM = FSXM = FSRM = 0 for slave McBSP

[#]FSX should be low before the rising edge of clock to enable slave devices and then begin a SPI transfer at the rising edge of the master clock (CLKX).

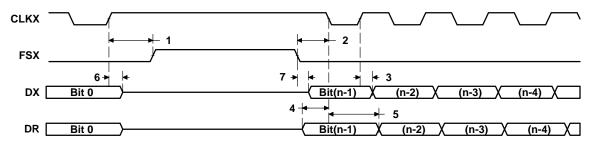


Figure 36. McBSP Timing as SPI Master or Slave: CLKSTP = 11b, CLKXP = 1



[†] The effects of internal clock jitter are included at test. There is no need to adjust timing numbers for internal clock jitter. P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

[‡] For all SPI slave modes, CLKG is programmed as 1/2 of the CPU clock by setting CLKSM = CLKGDV = 1.

[§]S = sample rate generator input clock = P if CLKSM = 1 (P = 1/CPU clock frequency)

⁼ sample rate generator input clock = P_clks if CLKSM = 0 (P_clks = CLKS period)

[¶] FSRP = FSXP = 1. As a SPI master, FSX is inverted to provide active-low slave-enable output. As a slave, the active-low signal input on FSX and FSR is inverted before being used internally.

DMAC, TIMER, POWER-DOWN TIMING

switching characteristics for DMAC outputs (see Figure 37)

NO. PARAMETER	PARAMETER	'C6701 'C6701		UNIT
		MIN	MAX	
1	td(CKO1H-DMACV) Delay time, CLKOUT1 high to DMAC valid	2	11	ns

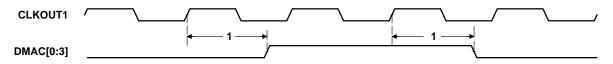


Figure 37. DMAC Timing

timing requirements for timer inputs (see Figure 38)†

NO.	NO.		'C6701-14 'C6701-16	
		MIN	MAX	
1	t _W (TINPH) Pulse duration, TINP high	2P		ns

 $[\]dagger$ P = 1/CPU clock frequency in ns. For example, when running parts at 167 MHz, use P = 6 ns.

switching characteristics for timer outputs (see Figure 38)

NO.	PARAMETER		'C6701-14 'C6701-16		
		MIN	MAX		
2	td(CKO1H-TOUTV) Delay time	e, CLKOUT1 high to TOUT valid	10	ns	

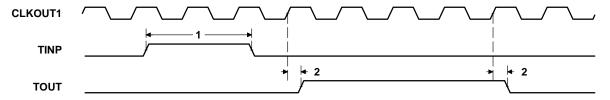


Figure 38. Timer Timing

switching characteristics for power-down outputs (see Figure 39)

NO.	PARAMETER		'C6701-14 'C6701-16	
		MIN	MAX	
1	td(CKO1H-PDV) Delay time, CLKOUT1 high to PD valid	1	9	ns

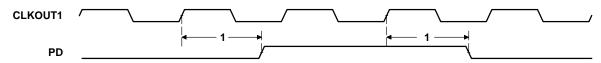


Figure 39. Power-Down Timing

JTAG TEST-PORT TIMING

timing requirements for JTAG test port (see Figure 40)

NO.			'C670 'C670		UNIT
			MIN	MAX	
1	t _C (TCK)	Cycle time, TCK	35		ns
3	tsu(TDIV-TCKH)	Setup time, TDI/TMS/TRST valid before TCK high	10		ns
4	th(TCKH-TDIV)	Hold time, TDI/TMS/TRST valid after TCK high	9		ns

switching characteristics for JTAG test port (see Figure 40)

NO.	PARAMETER	'C6701-14 'C6701-16		UNIT
		MIN	MAX	
2	t _{d(TCKL-TDOV)} Delay time, TCK low to TDO valid	*-3	*15	ns

^{*}This parameter is not tested.

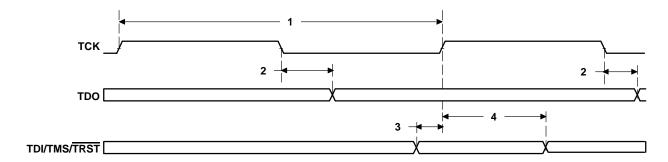
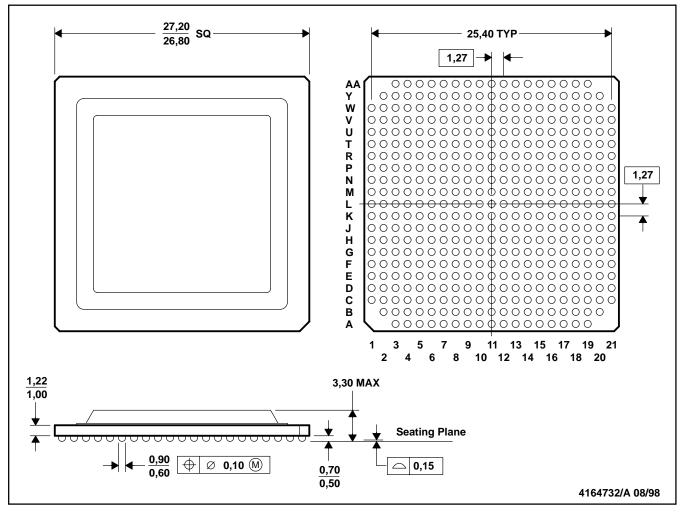


Figure 40. JTAG Test-Port Timing

MECHANICAL DATA

GLP (S-CBGA-N429)

CERAMIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-156
- D. Flip chip application only

thermal resistance characteristics (S-CBGA package)

NO			°C/W	Air Flow
1	RΘJC	Junction-to-Case, measured to the bottom of solder ball	3.0	N/A
2	RΘJC	Junction-to-Case, measured to the top of the package lid	7.3	N/A
3	$R\Theta_{JA}$	Junction-to-Ambient	14.5	0
4			11.8	150 fpm
5	RΘJMA	Junction-to-Moving-Air	11.1	250 fpm
6			10.2	500 fpm
7	R⊝JB	Junction-to-Board, measured by soldering a thermocouple to one of the middle traces on the board at the edge of the package	6.2	N/A





PACKAGE OPTION ADDENDUM

14-Aug-2007

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
5962-9866101QXA	ACTIVE	FC/CSP	GLP	429	1	TBD	Call TI	N / A for Pkg Type
5962-9866101VXA	ACTIVE	FC/CSP	GLP	429	1	TBD	Call TI	N / A for Pkg Type
5962-9866102VXA	ACTIVE	FC/CSP	GLP	429	1	TBD	Call TI	N / A for Pkg Type
SM320C6701GLPS16	ACTIVE	FC/CSP	GLP	429	1	TBD	Call TI	N / A for Pkg Type
SM320C6701GLPW14	ACTIVE	FC/CSP	GLP	429	1	TBD	Call TI	N / A for Pkg Type
SMJ320C6701GLPW14	ACTIVE	FC/CSP	GLP	429	1	TBD	Call TI	N / A for Pkg Type

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

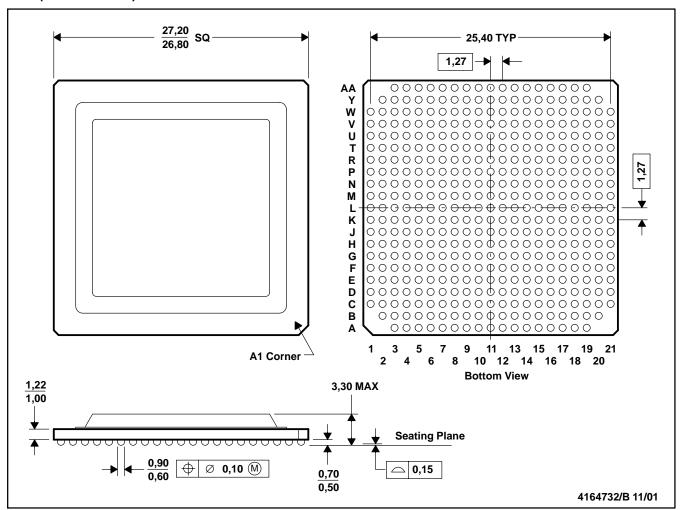
(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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GLP (S-CBGA-N429)

CERAMIC BALL GRID ARRAY



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Falls within JEDEC MO-156
- D. Flip chip application only



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